



MEASUREMENT REPORT

FCC Part 22, 24, & 27 LTE

Applicant Name:

Samsung Electronics Co., Ltd.
129, Samsung-ro,
Yeongtong-gu, Suwon-si
Gyeonggi-do, 16677, Korea

Date of Testing:

1/29-2/27/2016

Test Site/Location:

PCTEST Lab., Columbia, MD, USA

Test Report Serial No.:

0Y1601280165-R1.A3L

FCC ID :

A3LSMJ320VPP

APPLICANT:

SAMSUNG ELECTRONICS CO., LTD.

Application Type:

Certification

FCC Classification:

PCS Licensed Transmitter Held to Ear (PCE)

FCC Rule Part(s):

§2; §22; §24; §27

Test Procedure(s):

ANSI/TIA-603-C-2004, KDB 971168 D01 v02r02

EUT Type:

Portable Handset

Model(s):

SM-J320VPP

Test Device Serial No.:

identical prototype [S/N: 38422]

Mode	Tx Frequency (MHz)	Emission Designator	Modulation	ERP	
				Max. Power (W)	Max. Power (dBm)
LTE Band 13	779.5 - 784.5	4M50G7D	QPSK	0.087	19.41
LTE Band 13	779.5 - 784.5	4M49W7D	16QAM	0.067	18.29
LTE Band 13	782	8M98G7D	QPSK	0.072	18.60
LTE Band 13	782	8M95W7D	16QAM	0.058	17.65
LTE Band 5	824.7 - 848.3	1M13G7D	QPSK	0.042	16.28
LTE Band 5	824.7 - 848.3	1M12W7D	16QAM	0.034	15.29
LTE Band 5	825.5 - 847.5	2M72G7D	QPSK	0.048	16.84
LTE Band 5	825.5 - 847.5	2M72W7D	16QAM	0.038	15.75
LTE Band 5	826.5 - 846.5	4M51G7D	QPSK	0.050	17.00
LTE Band 5	826.5 - 846.5	4M51W7D	16QAM	0.038	15.74
LTE Band 5	829 - 844	9M02G7D	QPSK	0.049	16.92
LTE Band 5	829 - 844	8M98W7D	16QAM	0.037	15.71

Mode	Tx Frequency (MHz)	Emission Designator	Modulation	EIRP	
				Max. Power (W)	Max. Power (dBm)
LTE Band 4	1710.7 - 1754.3	1M12G7D	QPSK	0.143	21.56
LTE Band 4	1710.7 - 1754.3	1M13W7D	16QAM	0.111	20.46
LTE Band 4	1711.5 - 1753.5	2M73G7D	QPSK	0.146	21.65
LTE Band 4	1711.5 - 1753.5	2M73W7D	16QAM	0.110	20.41
LTE Band 4	1712.5 - 1752.5	4M53G7D	QPSK	0.162	22.09
LTE Band 4	1712.5 - 1752.5	4M54W7D	16QAM	0.123	20.89
LTE Band 4	1715 - 1750	9M01G7D	QPSK	0.153	21.85
LTE Band 4	1715 - 1750	8M99W7D	16QAM	0.117	20.70
LTE Band 4	1717.5 - 1747.5	13M5G7D	QPSK	0.164	22.14
LTE Band 4	1717.5 - 1747.5	13M4W7D	16QAM	0.125	20.95
LTE Band 4	1720 - 1745	18M0G7D	QPSK	0.171	22.32
LTE Band 4	1720 - 1745	18M0W7D	16QAM	0.126	20.99
LTE Band 2	1850.7 - 1909.3	1M12G7D	QPSK	0.190	22.79
LTE Band 2	1850.7 - 1909.3	1M12W7D	16QAM	0.159	22.00
LTE Band 2	1851.5 - 1908.5	2M72G7D	QPSK	0.196	22.91
LTE Band 2	1851.5 - 1908.5	2M71W7D	16QAM	0.148	21.70
LTE Band 2	1852.5 - 1907.5	4M51G7D	QPSK	0.202	23.05
LTE Band 2	1852.5 - 1907.5	4M51W7D	16QAM	0.156	21.94
LTE Band 2	1855 - 1905	9M00G7D	QPSK	0.187	22.71
LTE Band 2	1855 - 1905	8M95W7D	16QAM	0.140	21.47
LTE Band 2	1857.5 - 1902.5	13M5G7D	QPSK	0.205	23.13
LTE Band 2	1857.5 - 1902.5	13M5W7D	16QAM	0.157	21.97
LTE Band 2	1860 - 1900	17M9G7D	QPSK	0.210	23.21
LTE Band 2	1860 - 1900	18M0W7D	16QAM	0.159	22.02

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

This revised Test Report (S/N: 0Y1601280165-R1.A3L) supersedes and replaces the previously issued test report (S/N: 0Y1601280165.A3L) on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose accordingly.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.


Randy Ortanez
President

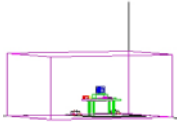


FCC ID: A3LSMJ320VPP		 FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)			Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset			Page 1 of 115

T A B L E O F C O N T E N T S

FCC PART 22, 24, & 27 MEASUREMENT REPORT	3
1.0 INTRODUCTION	4
1.1 Scope.....	4
1.2 Testing Facility	4
2.0 PRODUCT INFORMATION.....	5
2.1 Equipment Description	5
2.2 Device Capabilities	5
2.3 Test Configuration.....	5
2.4 EMI Suppression Device(s)/Modifications.....	5
3.0 DESCRIPTION OF TESTS	6
3.1 Measurement Procedure.....	6
3.1 Block C Frequency Range	6
3.2 Cellular - Base Frequency Blocks	6
3.3 Cellular - Mobile Frequency Blocks.....	6
3.4 PCS - Base Frequency Blocks	7
3.5 PCS - Mobile Frequency Blocks	7
3.6 AWS - Base Frequency Blocks	7
3.7 AWS - Mobile Frequency Blocks.....	7
3.8 Radiated Power and Radiated Spurious Emissions.....	8
4.0 MEASUREMENT UNCERTAINTY	9
5.0 TEST EQUIPMENT CALIBRATION DATA	10
6.0 SAMPLE CALCULATIONS	11
7.0 TEST RESULTS	12
7.1 Summary.....	12
7.2 Occupied Bandwidth	13
7.3 Spurious and Harmonic Emissions at Antenna Terminal	32
7.4 Band Edge Emissions at Antenna Terminal.....	48
7.5 Peak-Average Ratio.....	84
7.6 Radiated Power (ERP/EIRP)	91
7.7 Radiated Spurious Emissions Measurements.....	97
7.8 Frequency Stability / Temperature Variation	106
8.0 CONCLUSION.....	115

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset	Page 2 of 115	



MEASUREMENT REPORT

FCC Part 22, 24, & 27

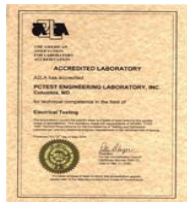


§2.1033 General Information

APPLICANT: Samsung Electronics Co., Ltd.
APPLICANT ADDRESS: 129, Samsung-ro,
 Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea
TEST SITE: PCTEST ENGINEERING LABORATORY, INC.
TEST SITE ADDRESS: 7185 Oakland Mills Road, Columbia, MD 21045 USA
FCC RULE PART(S): §2; §22; §24; §27
BASE MODEL: SM-J320VPP
FCC ID: A3LSMJ320VPP
FCC CLASSIFICATION: PCS Licensed Transmitter Held to Ear (PCE)
FREQUENCY TOLERANCE: $\pm 0.00025\%$ (2.5 ppm)
Test Device Serial No.: 38422 ☐ Production ☒ Pre-Production ☐ Engineering
DATE(S) OF TEST: 1/29-2/27/2016
TEST REPORT S/N: 0Y1601280165-R1.A3L

Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.



- PCTEST facility is an FCC registered (PCTEST Reg. No. 159966) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (2451B-1).
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing Aid Compatibility (HAC) testing, CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (2451B-1) test laboratory with the site description on file at Industry Canada.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS, CDMA, and EvDO wireless devices and for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO, and CDMA 1xRTT.

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 3 of 115

1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EME) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 Testing Facility

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity, the Baltimore-Washington Intern't'l (BWI) airport, the city of Baltimore and the Washington, DC area. (See Figure 1-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The site coordinates are 39° 10'23" N latitude and 76° 49'50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2014 on January 22, 2015.

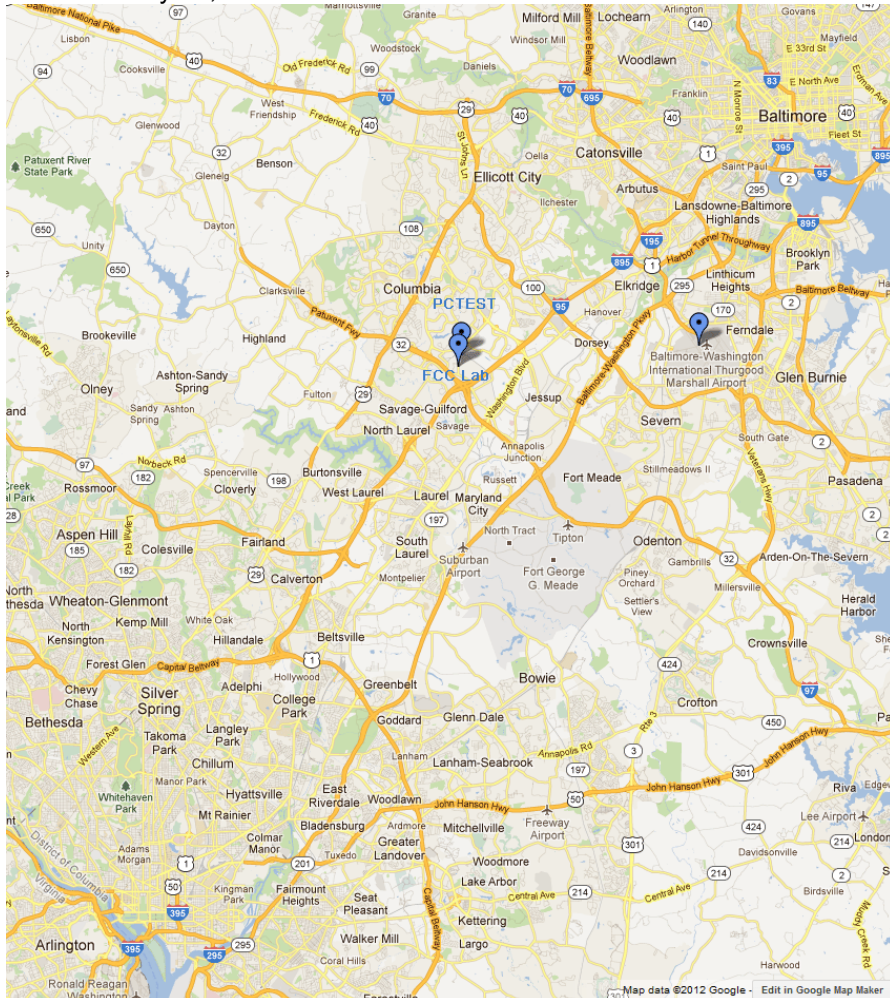


Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 4 of 115

2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSMJ320VPP**. The test data contained in this report pertains only to the emissions due to the EUT's LTE function.

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 CDMA/EvDO Rev0/A (BC0, BC1), 850/1900 GSM/GPRS/EDGE, 850/1900 WCDMA/HSPA, Multi-band LTE, 802.11b/g/n WLAN, 802.11a/n UNII, Bluetooth (1x, EDR, LE)

2.3 Test Configuration

The Samsung Portable Handset FCC ID: A3LSMJ320VPP was tested per the guidance of ANSI/TIA-603-C-2004 and KDB 971168 D01 v02r02. See Section 7.0 of this test report for a description of the radiated and antenna port conducted emissions tests.

2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset	Page 5 of 115	

3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the document titled “Land Mobile FM or PM – Communications Equipment – Measurements and Performance Standards” (ANSI/TIA-603-C-2004) and “Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems” (KDB 971168 D01 v02r02) were used in the measurement of the **Samsung Portable Handset FCC ID: A3LSMJ320VPP**.

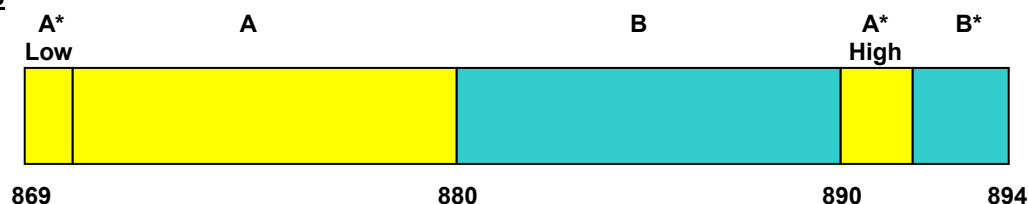
3.1 Block C Frequency Range

§27.5(b)(3)

Two paired channels of 11 megahertz each are available for assignment in Block C in the 746-757 MHz and 776-787 MHz bands. In the event that no licenses for two channels in this Block C are assigned based on the results of the first auction in which such licenses were offered because the auction results do not satisfy the applicable reserve price, the spectrum in the 746-757 MHz and 776-787 MHz bands will instead be made available for assignment at a subsequent auction as follows: (i) Two paired channels of 6 megahertz each available for assignment in Block C1 in the 746-752 MHz and 776-782 MHz bands. (ii) Two paired channels of 5 megahertz each available for assignment in Block C2 in the 752-757 MHz and 782-787 MHz bands.

3.2 Cellular - Base Frequency Blocks

§22.905

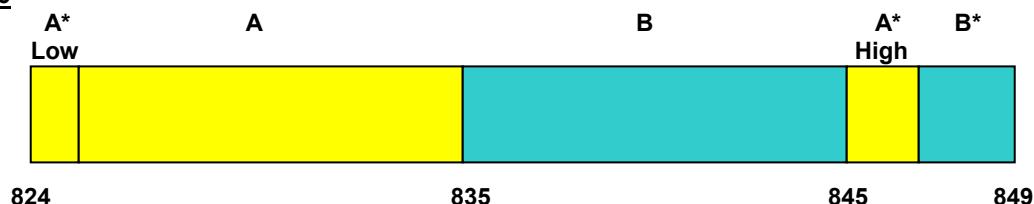


BLOCK 1: 869 – 880 MHz (A* Low + A)
BLOCK 2: 880 – 890 MHz (B)

BLOCK 3: 890 – 891.5 MHz (A* High)
BLOCK 4: 891.5 – 894 MHz (B*)

3.3 Cellular - Mobile Frequency Blocks

§22.905



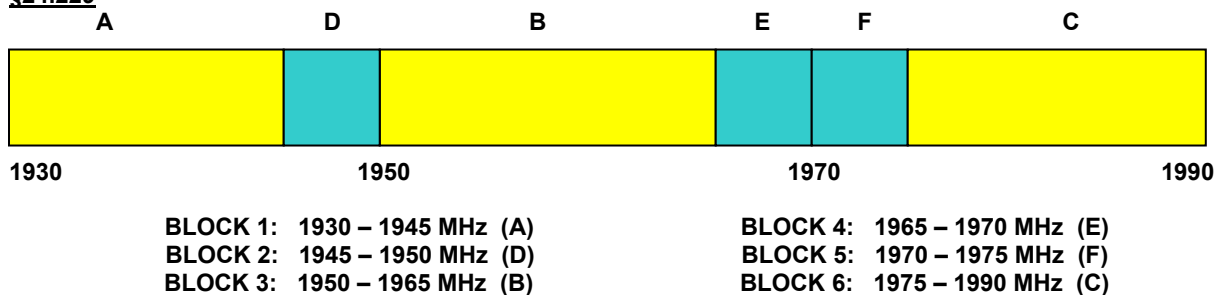
BLOCK 1: 824 – 835 MHz (A* Low + A)
BLOCK 2: 835 – 845 MHz (B)

BLOCK 3: 845 – 846.5 MHz (A* High)
BLOCK 4: 846.5 – 849 MHz (B*)

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 6 of 115

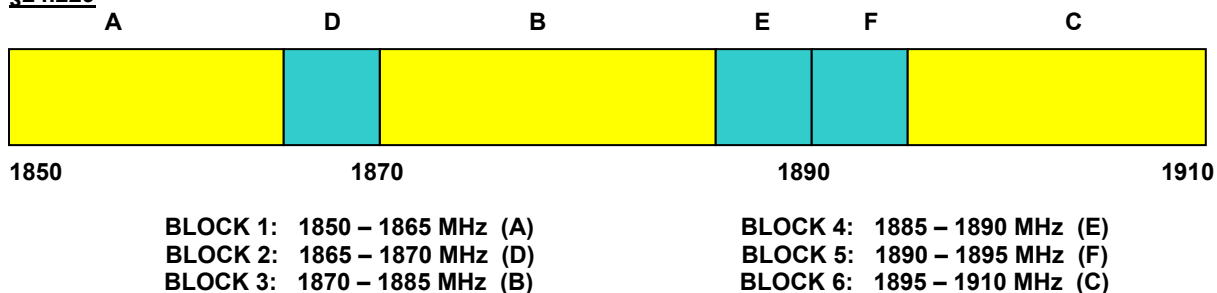
3.4 PCS - Base Frequency Blocks

§24.229



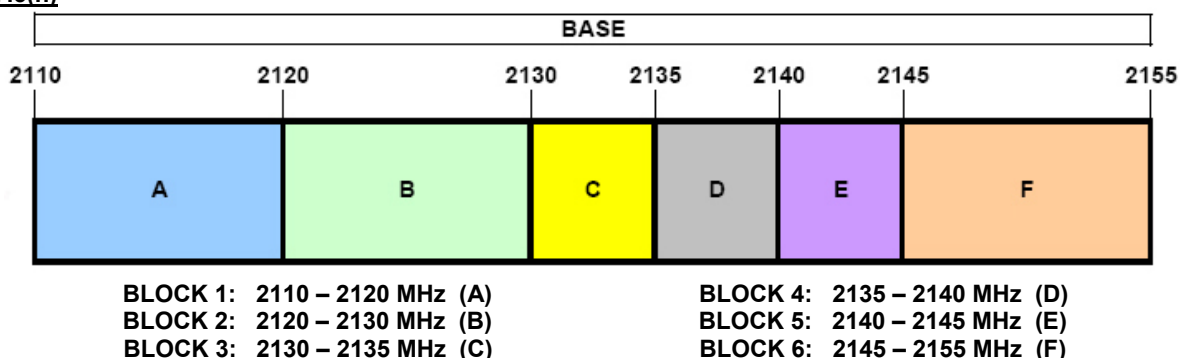
3.5 PCS - Mobile Frequency Blocks

§24.229



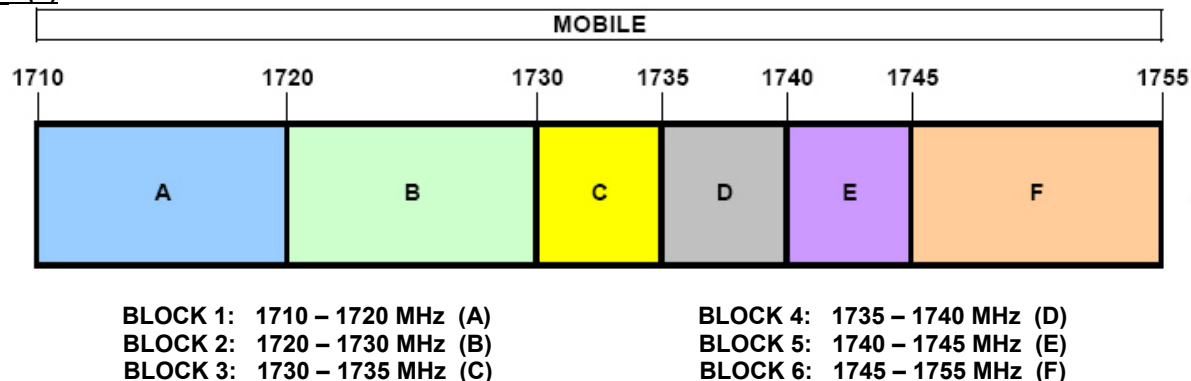
3.6 AWS - Base Frequency Blocks

§27.5(h)



3.7 AWS - Mobile Frequency Blocks

§27.5(h)



FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 7 of 115

3.8 Radiated Power and Radiated Spurious Emissions

§2.1053 §22.913(a.2) §22.917(a) §24.232(c) §24.238(a) §27.50(b.10) §27.50(d.4) §27.53(f) §27.53(h)

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Clause 5, Figure 5.7 of ANSI C63.4-2009. For measurements above 1GHz absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1GHz, the absorbers are removed. An ETS Lindgren Model 2188 raised turntable is used for radiated measurement. It is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. A 78cm high PVC support structure is placed on top of the turntable. A ¾" (~1.9cm) sheet of high density polyethylene is used as the table top and is placed on top of the PVC supports to bring the total height of the table to 80cm.

The equipment under test was transmitting while connected to its integral antenna and is placed on a turntable 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer. Radiated power levels are also investigated with the receive antenna horizontally and vertically polarized. The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration band set to the emissions' occupied bandwidth, a RMS detector, RBW = 100kHz, VBW = 300kHz, and a 1 second sweep time over a minimum of 10 sweeps, per the guidelines of KDB 971168.

Per the guidance of ANSI/TIA-603-C-2004, a half-wave dipole is then substituted in place of the EUT. For emissions above 1GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator with the level of the signal generator being adjusted to obtain the same receive spectrum analyzer level previously recorded from the spurious emission from the EUT. The power of the emission is calculated using the following formula:

$$P_d \text{ [dBm]} = P_g \text{ [dBm]} - \text{cable loss} \text{ [dB]} + \text{antenna gain} \text{ [dBd/dBi]}$$

Where, P_d is the dipole equivalent power, P_g is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to $P_g \text{ [dBm]} - \text{cable loss} \text{ [dB]}$.

The calculated P_d levels are then compared to the absolute spurious emission limit of -13dBm which is equivalent to the required minimum attenuation of $43 + 10\log_{10}(\text{Power} \text{ [Watts]})$.

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 8 of 115

4.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.4-2014. All measurement uncertainty values are shown with a coverage factor of $k = 2$ to indicate a 95% level of confidence. The measurement data shown herein meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty ($\pm$ dB)
Conducted Bench Top Measurements	1.13
Radiated Disturbance (<1GHz)	4.98
Radiated Disturbance (>1GHz)	5.07
Radiated Disturbance (>18GHz)	5.09

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset	Page 9 of 115	

5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	LTX3	Licensed Transmitter Cable Set	6/12/2015	Annual	6/12/2016	LTX3
-	RE1	Radiated Emissions Cable Set (UHF/EHF)	4/28/2015	Annual	4/28/2016	RE1
Agilent	N9020A	MXA Signal Analyzer	11/5/2015	Annual	11/5/2016	US46470561
Agilent	N9030A	PXA Signal Analyzer (44GHz)	3/24/2015	Annual	3/24/2016	MY52350166
Anritsu	MT8820C	Radio Communication Analyzer	7/24/2015	Annual	7/24/2016	6200901190
Emco	3115	Horn Antenna (1-18GHz)	3/30/2014	Biennial	3/30/2016	9704-5182
Espec	ESX-2CA	Environmental Chamber	3/17/2015	Annual	3/17/2016	17620
ETS Lindgren	3164-08	Quad Ridge Horn Antenna	10/22/2014	Biennial	10/22/2016	128338
K & L	11SH10-3075/U18000	High Pass Filter	7/18/2015	Annual	7/18/2016	11SH10-3075/U18000-2
K & L	13SH10-1000/U1000	N Type High Pass Filter	7/18/2015	Annual	7/18/2016	13SH10-1000/U1000-2
Mini-Circuits	PWR-SENS-4RMS	USB Power Sensor	3/11/2015	Annual	3/11/2016	11210140001
Mini-Circuits	SSG-4000HP	Synthesized Signal Generator	N/A			11208010032
Mini-Circuits	TVA-11-422	RF Power Amp	N/A			QA1303002
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	3/12/2015	Annual	3/12/2016	100342
Rohde & Schwarz	TS-PR18	1-18 GHz Pre-Amplifier	3/5/2015	Annual	3/5/2016	100071
Schwarzbeck	UHA 9105	Dipole Antenna (400 - 1GHz) Rx	2/21/2014	Biennial	2/21/2016	9105-2404

Table 5-1. Test Equipment

Notes:

1. For equipment listed above that has a calibration date or calibration due date that falls within the test date range, care was taken to ensure that this equipment was used after the calibration date and before the calibration due date.
2. Equipment with a calibration date of "N/A" shown in this list was not used to make direct calibrated measurements.

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset	Page 10 of 115	

6.0 SAMPLE CALCULATIONS

Emission Designator

QPSK Modulation

Emission Designator = 8M62G7D

LTE BW = 8.62 MHz

G = Phase Modulation

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

16QAM Modulation

Emission Designator = 8M45W7D

LTE BW = 8.45 MHz

W = Amplitude/Angle Modulated

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

Spurious Radiated Emission – LTE Band

Example: Middle Channel LTE Mode 2nd Harmonic (1564 MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 1564 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm – (-24.80).

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 11 of 115

7.0 TEST RESULTS

7.1 Summary

Company Name: Samsung Electronics Co., Ltd.
 FCC ID: A3LSMJ320VPP
 FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)
 Mode(s): LTE

FCC Part Section(s)	Test Description	Test Limit	Test Condition	Result	Reference
TRANSMITTER MODE (TX)					
2.1049	Occupied Bandwidth	N/A	CONDUCTED	PASS	Section 7.2
2.1051 22.917(a) 24.238(a) 27.53(c) 27.53(h)	Out of Band Emissions	$> 43 + 10\log_{10}(P[\text{Watts}])$ at Band Edge and for all out-of-band emissions		PASS	Section 7.3, 7.4
24.232(d)	Peak-Average Ratio	< 13 dB		PASS	Section 7.5
2.1046	Transmitter Conducted Output Power	N/A		PASS	See RF Exposure Report
2.1055. 22.355 24.235 27.54	Frequency Stability	< 2.5 ppm (Part 22) and fundamental emissions stay within authorized frequency block (Part 24, 27)		PASS	Section 7.8
22.913(a.2)	Effective Radiated Power (Band 5)	< 7 Watts max. ERP	RADIATED	PASS	Section 7.6
27.50(b.10)	Effective Radiated Power (Band 13)	< 3 Watts max. ERP		PASS	Section 7.6
24.232(c)	Equivalent Isotropic Radiated Power (Band 2)	< 2 Watts max. EIRP		PASS	Section 7.6
27.50(d.4)	Equivalent Isotropic Radiated Power (Band 4)	< 1 Watts max. EIRP		PASS	Section 7.6
2.1053 22.917(a) 24.238(a) 27.53(c) 27.53(h)	Undesirable Emissions	$> 43 + 10\log_{10}(P[\text{Watts}])$ for all out-of-band emissions		PASS	Section 7.7
27.53(f)	Undesirable Emissions (Band 13)	< -70 dBW/MHz (for wideband signals) < -80 dBW (for discrete emissions less than 700Hz BW) For all emissions in the band 1559 – 1610 MHz		PASS	Section 7.7

Table 7-1. Summary of Test Results

Notes:

- 1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
- 2) The analyzer plots (Sections 7.2, 7.3, 7.4, 7.5) were all taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
- 3) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
- 4) For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "LTE Automation," Version 4.0.

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset	Page 12 of 115	

7.2 Occupied Bandwidth

\$2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Procedure Used

KDB 971168 D01 v02r02 – Section 4.2

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW $\geq 3 \times$ RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

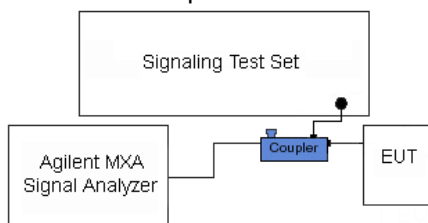
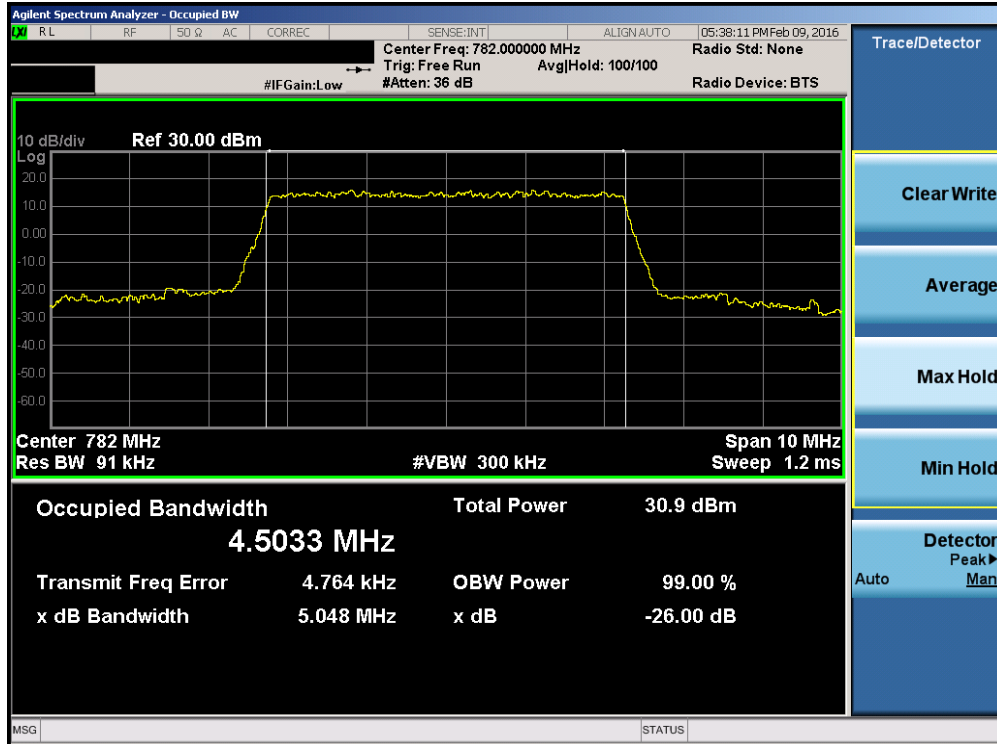


Figure 7-1. Test Instrument & Measurement Setup

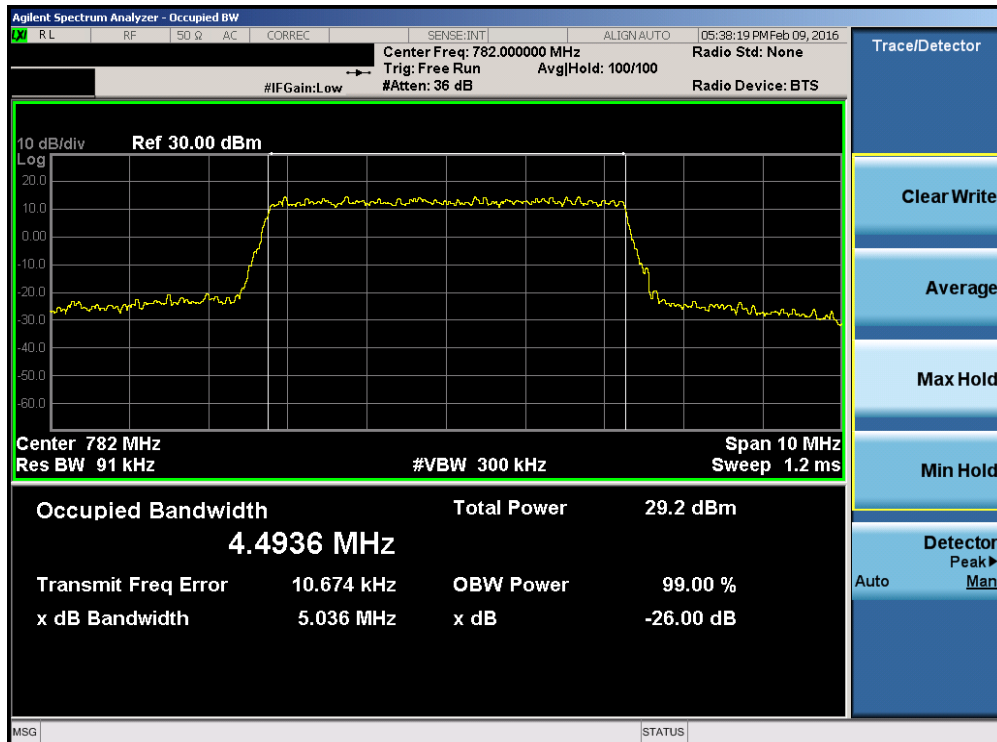
Test Notes

None.

FCC ID: A3LSMJ320VPP		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset	Page 13 of 115	

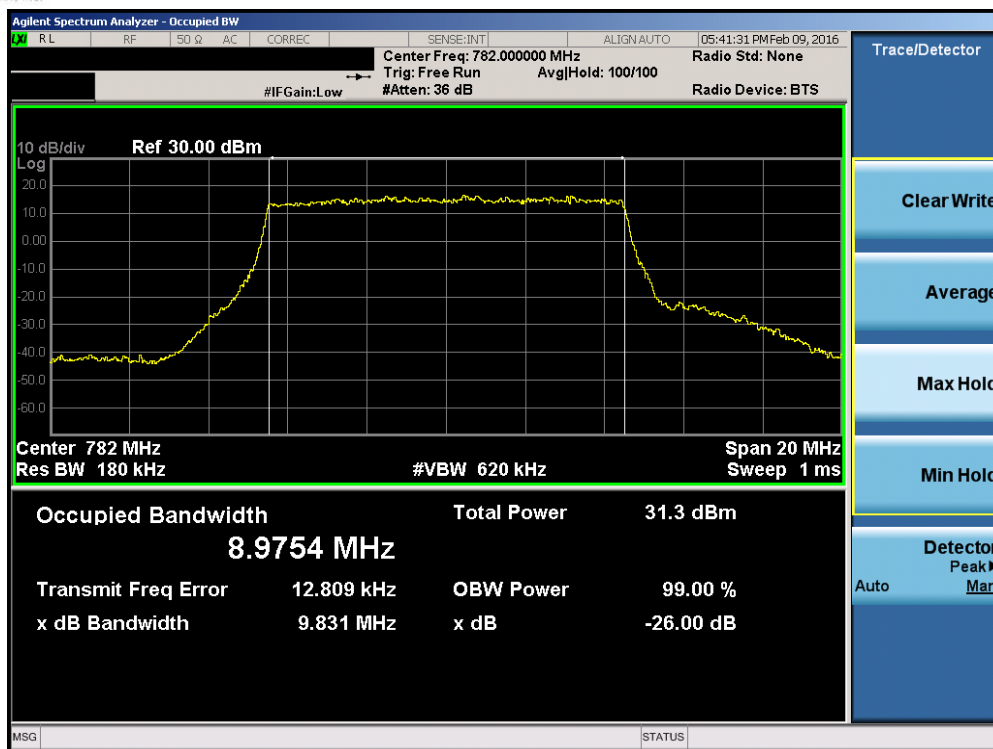


Plot 7-1. Occupied Bandwidth Plot (Band 13 – 5.0MHz QPSK – RB Size 25)

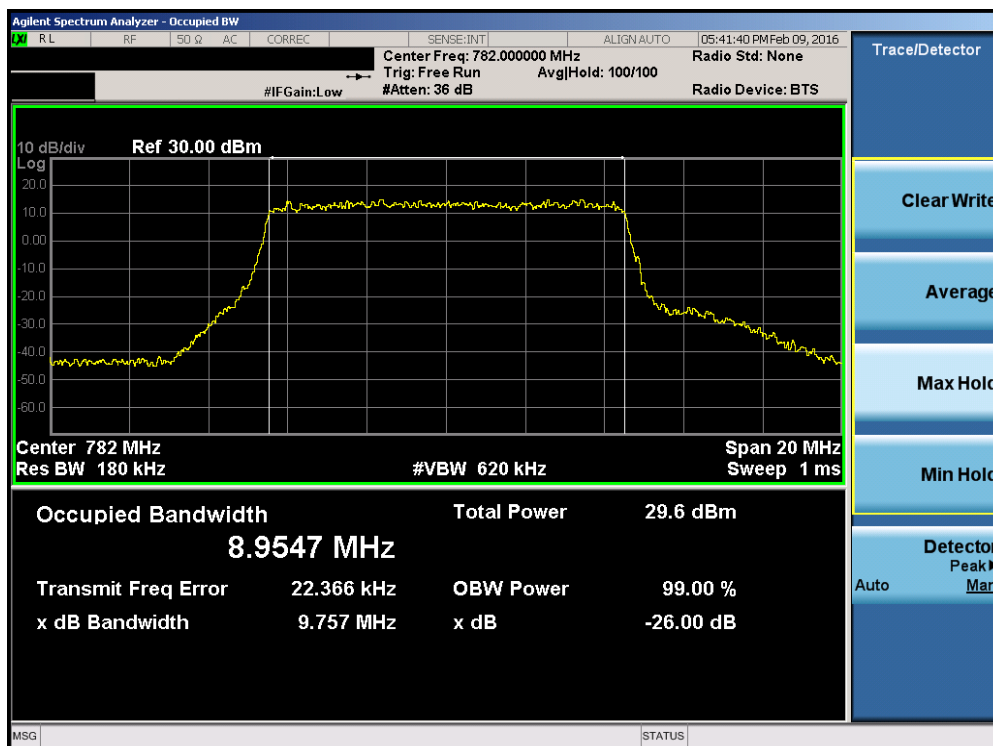


Plot 7-2. Occupied Bandwidth Plot (Band 13 – 5.0MHz 16-QAM – RB Size 25)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 14 of 115

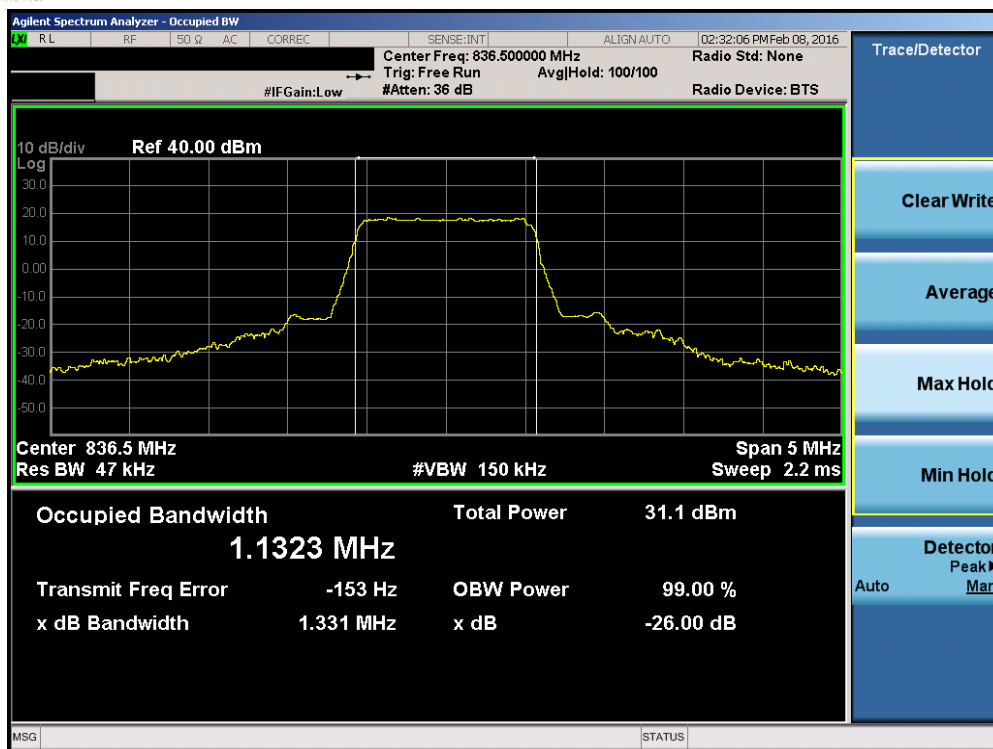


Plot 7-3. Occupied Bandwidth Plot (Band 13 – 10.0MHz QPSK – RB Size 50)

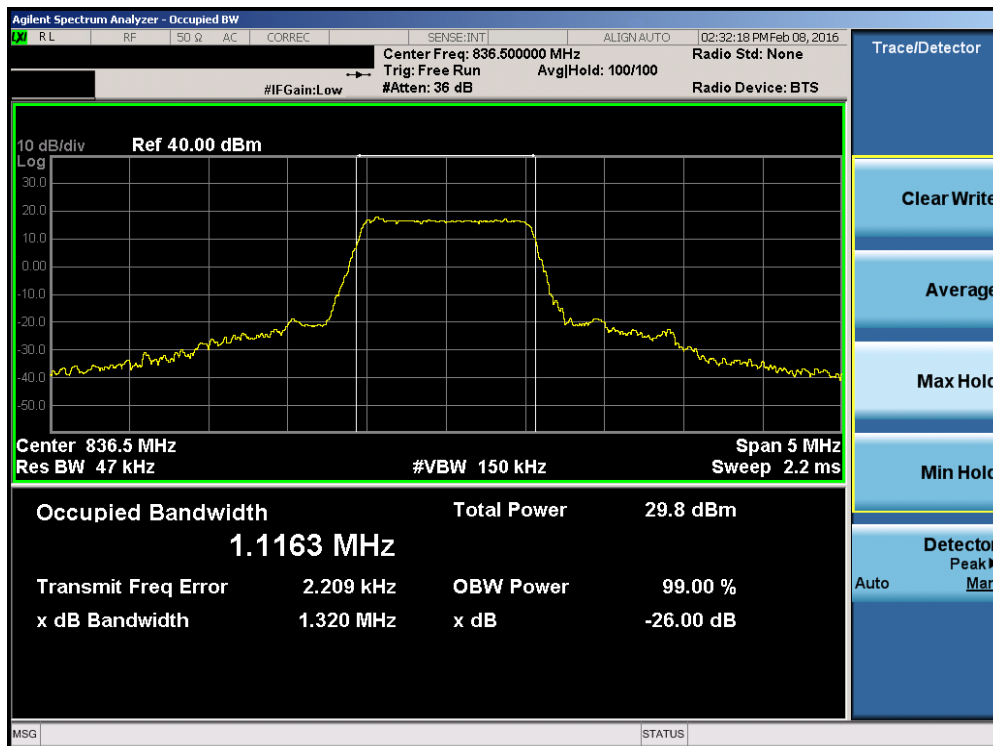


Plot 7-4. Occupied Bandwidth Plot (Band 13 – 10.0MHz 16-QAM – RB Size 50)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 15 of 115

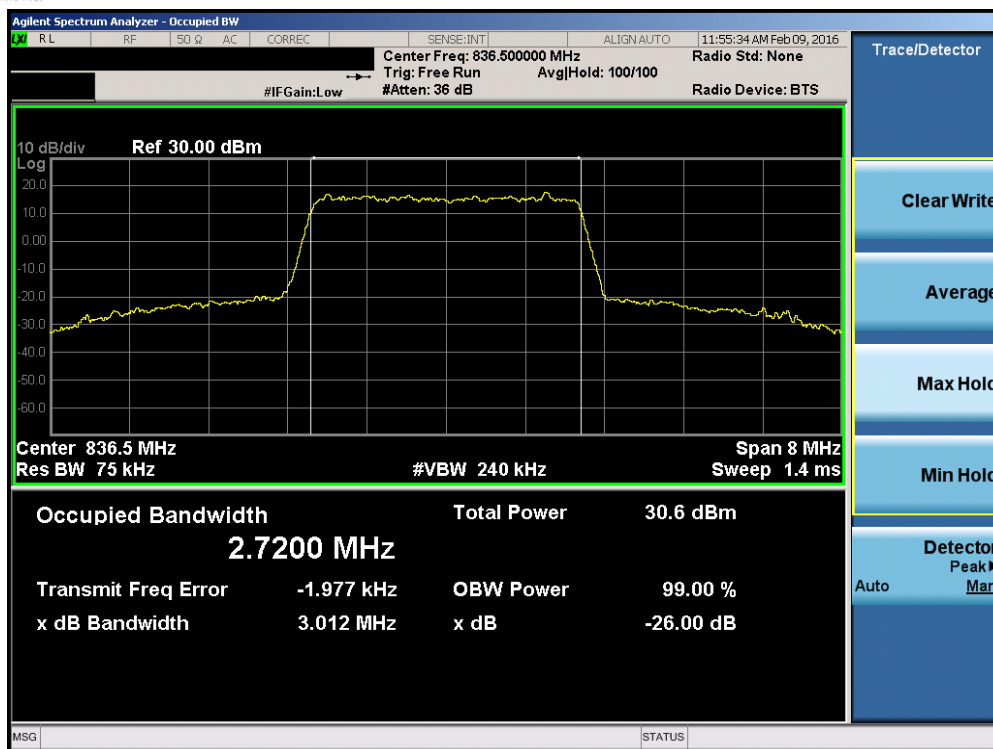


Plot 7-5. Occupied Bandwidth Plot (Band 5 – 1.4MHz QPSK – RB Size 6)

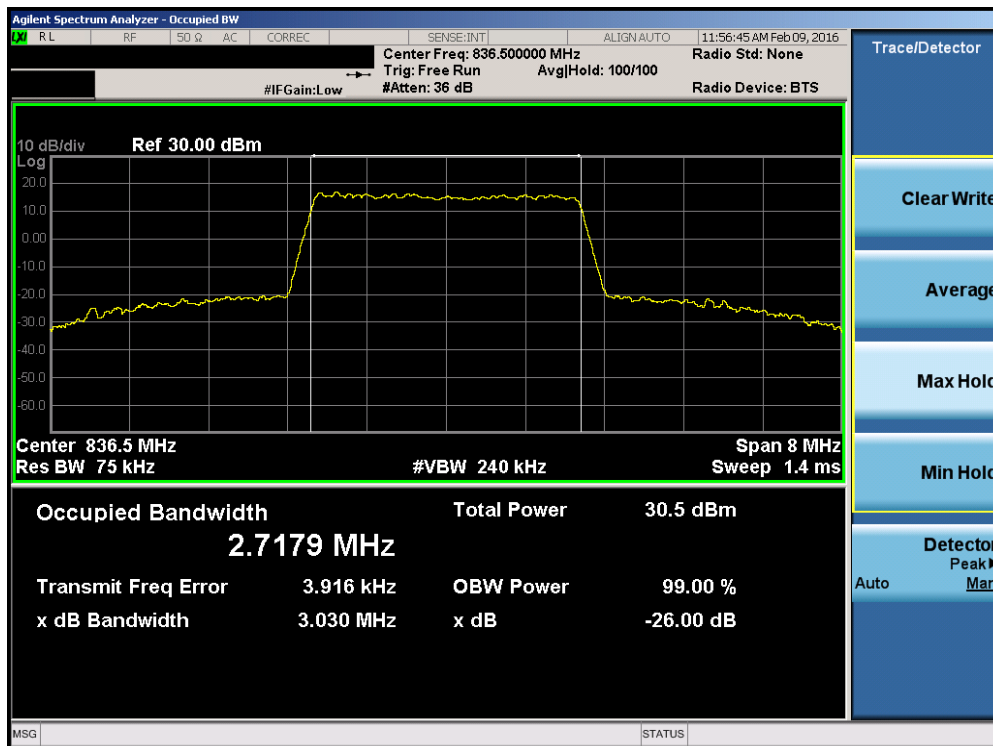


Plot 7-6. Occupied Bandwidth Plot (Band 5 – 1.4MHz 16-QAM – RB Size 6)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 16 of 115

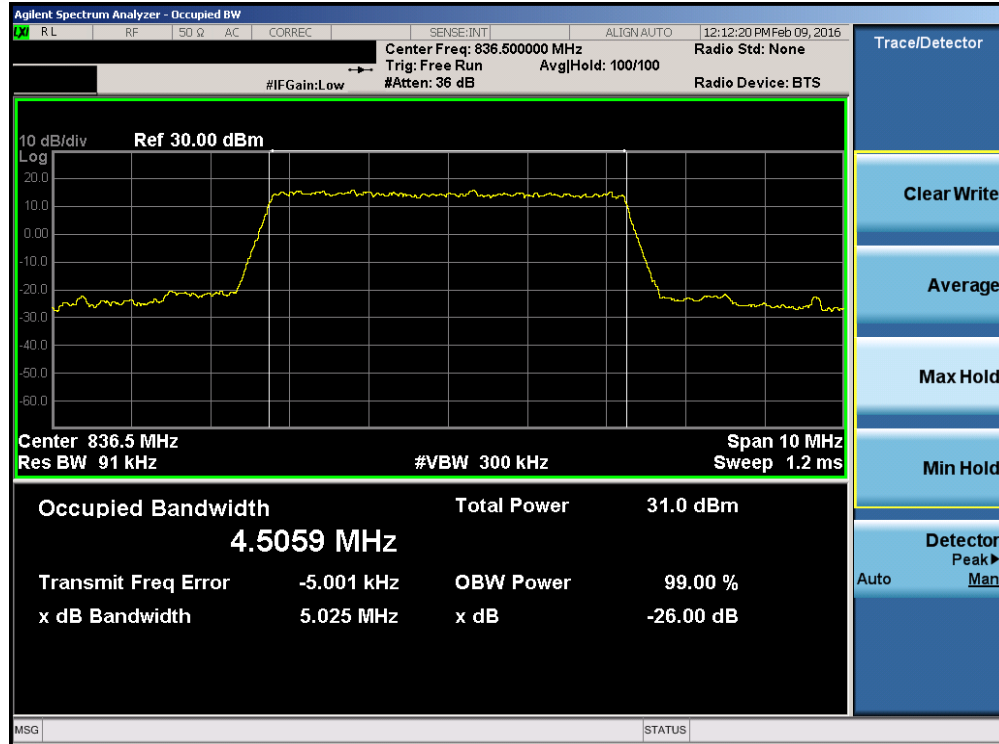


Plot 7-7. Occupied Bandwidth Plot (Band 5 – 3.0MHz QPSK – RB Size 15)

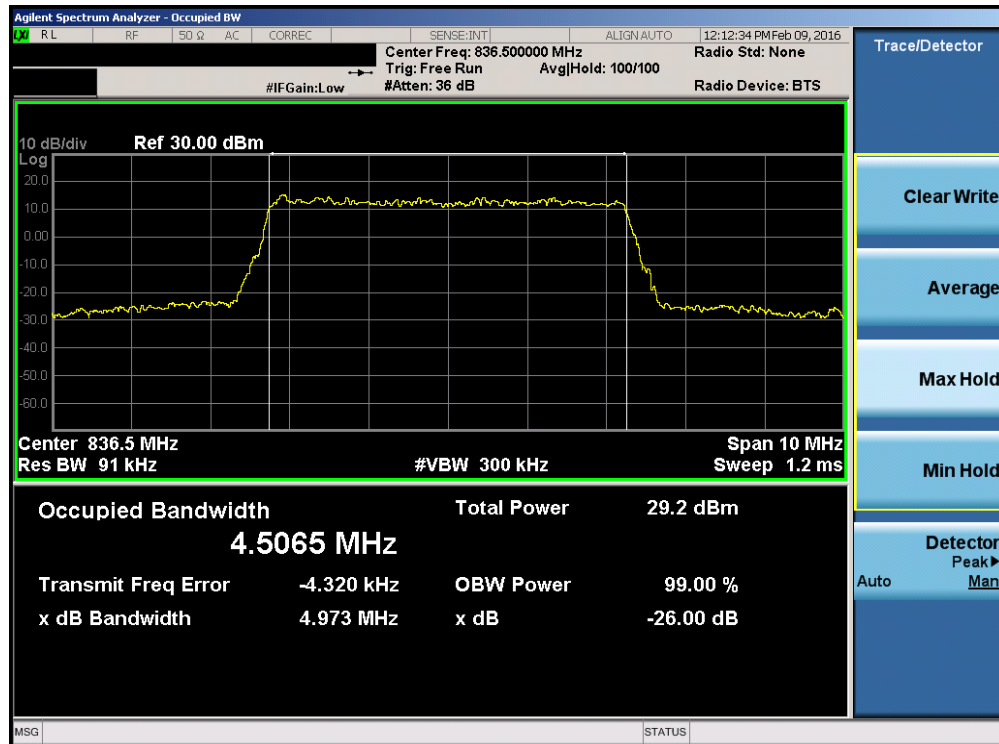


Plot 7-8. Occupied Bandwidth Plot (Band 5 – 3.0MHz 16-QAM – RB Size 15)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 17 of 115

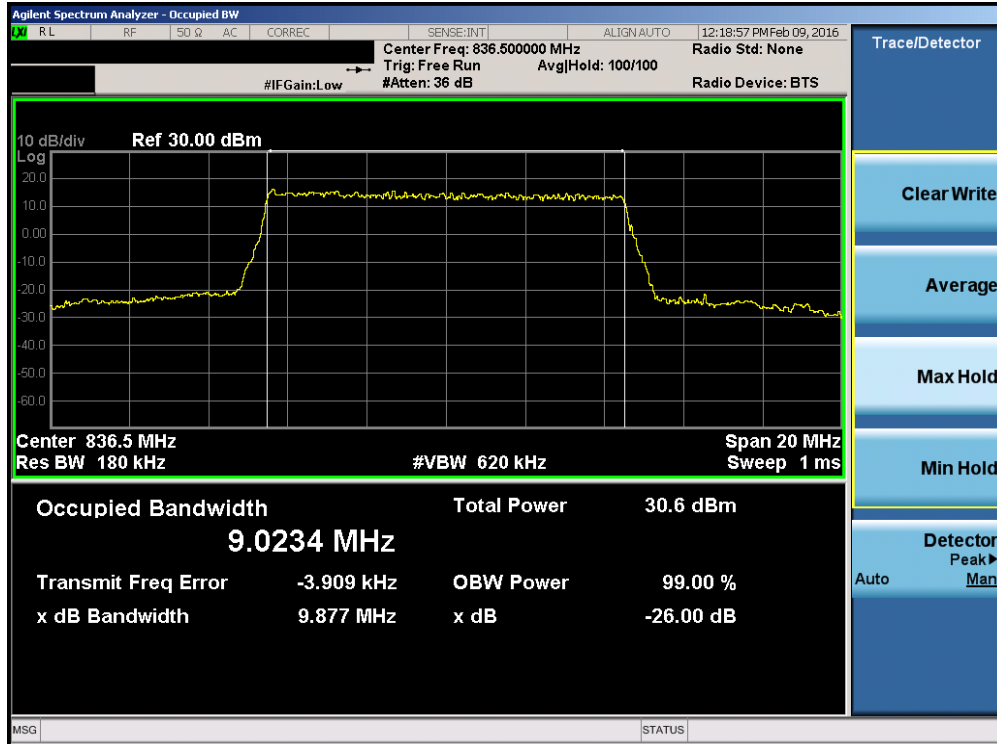


Plot 7-9. Occupied Bandwidth Plot (Band 5 – 5.0MHz QPSK – RB Size 25)

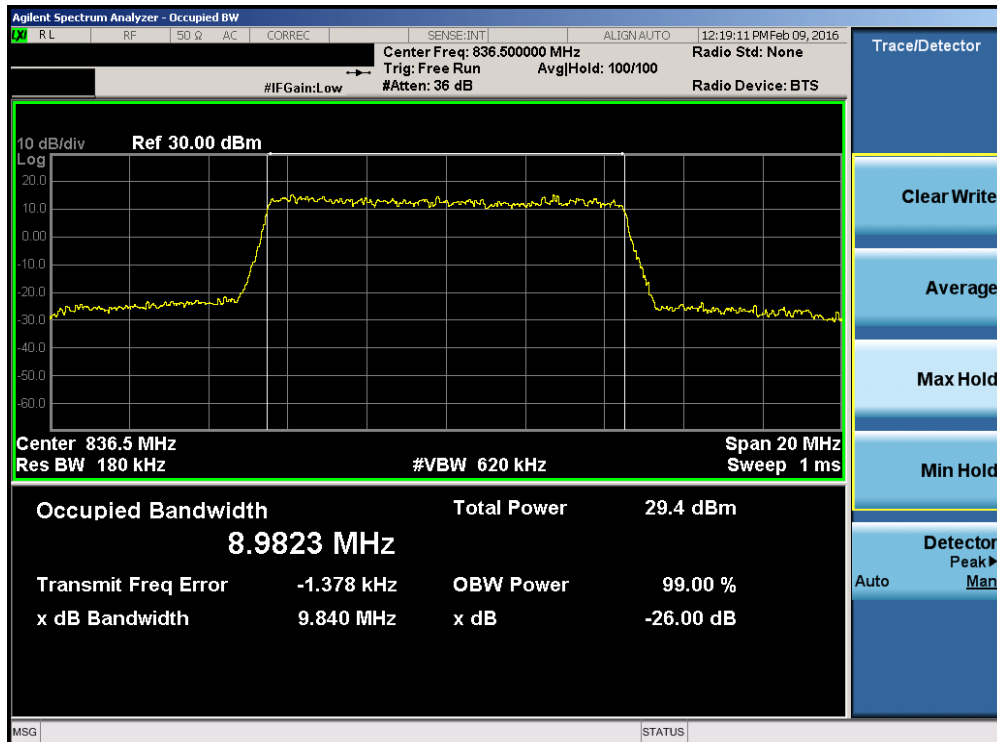


Plot 7-10. Occupied Bandwidth Plot (Band 5 – 5.0MHz 16-QAM – RB Size 25)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 18 of 115

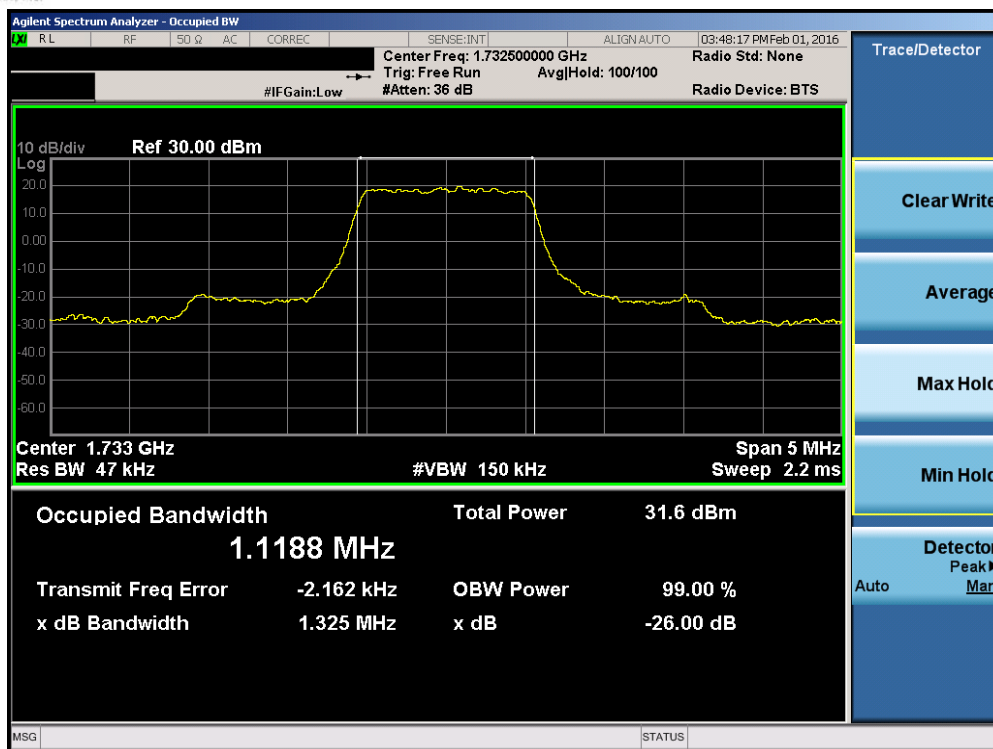


Plot 7-11. Occupied Bandwidth Plot (Band 5 – 10.0MHz QPSK – RB Size 50)

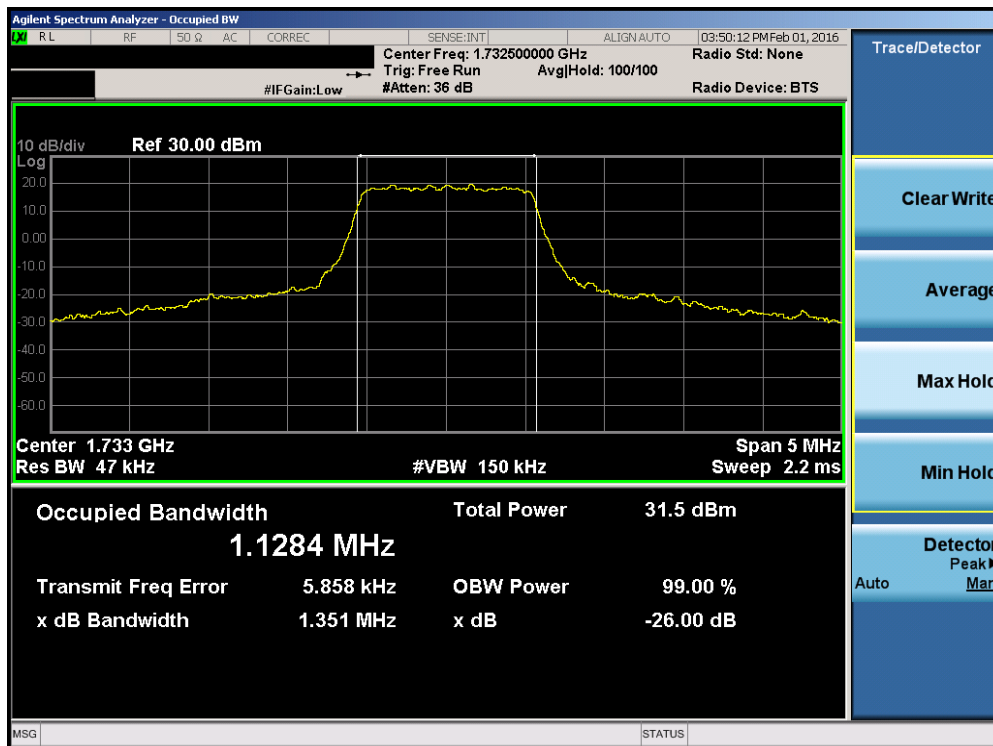


Plot 7-12. Occupied Bandwidth Plot (Band 5 – 10.0MHz 16-QAM – RB Size 50)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 19 of 115

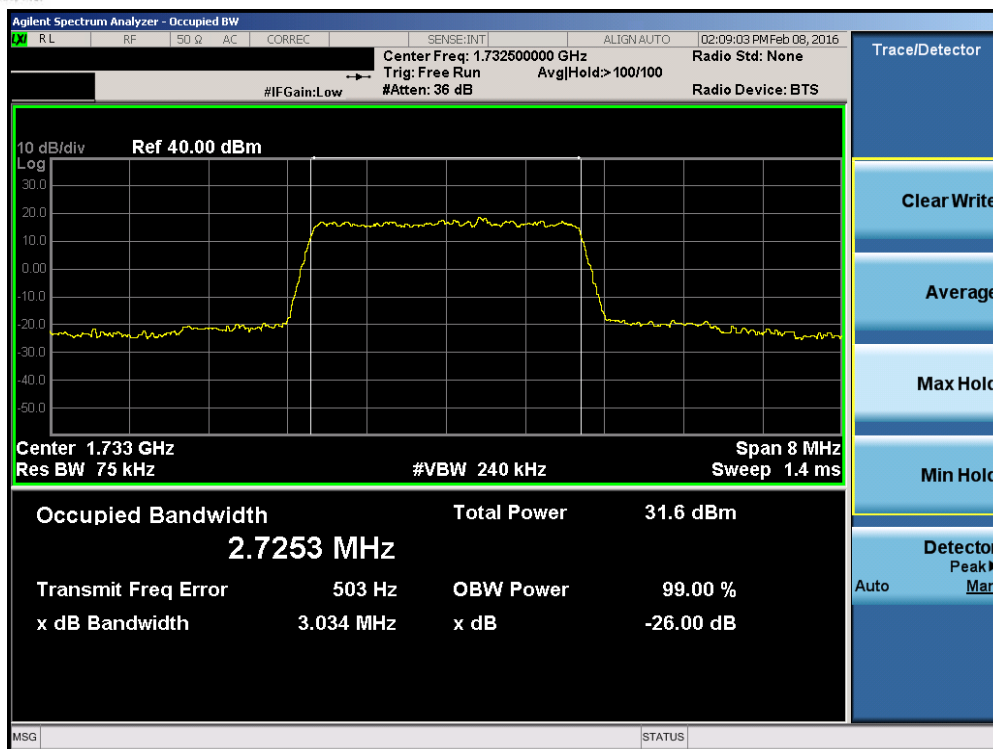


Plot 7-13. Occupied Bandwidth Plot (Band 4 – 1.4MHz QPSK – RB Size 6)

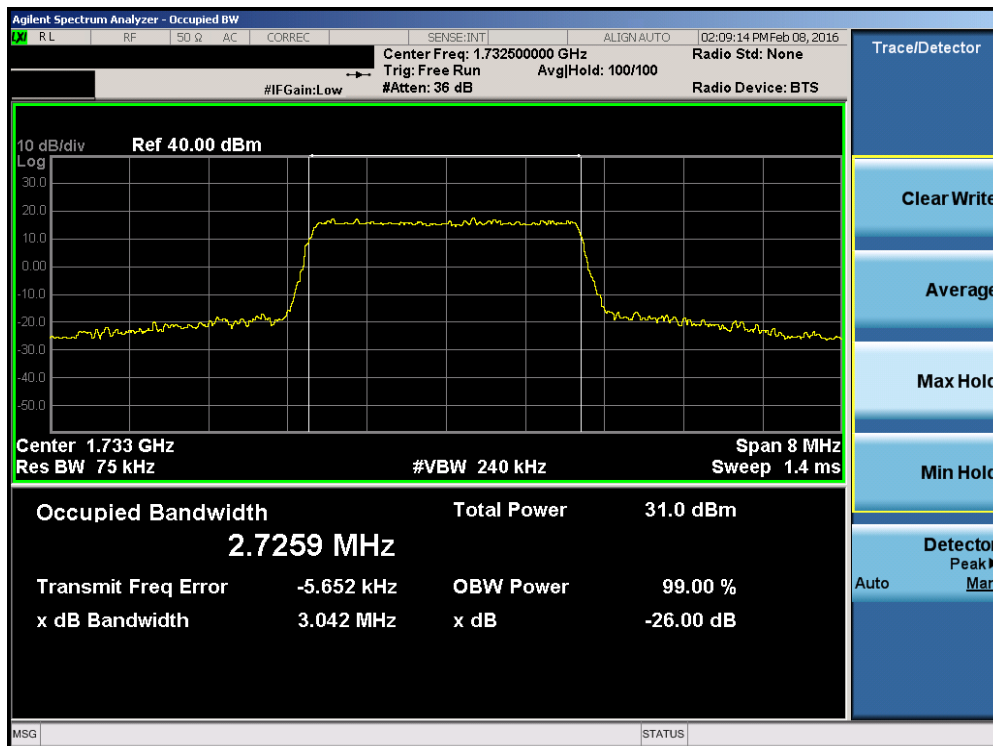


Plot 7-14. Occupied Bandwidth Plot (Band 4 – 1.4MHz 16-QAM – RB Size 6)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 20 of 115

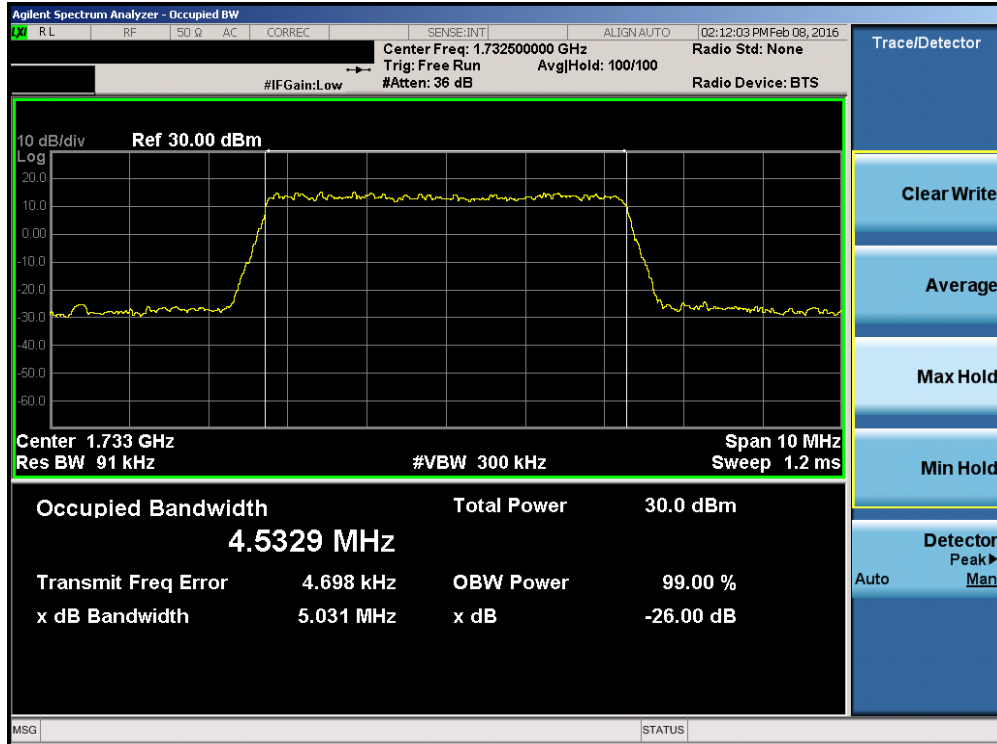


Plot 7-15. Occupied Bandwidth Plot (Band 4 – 3.0MHz QPSK – RB Size 15)

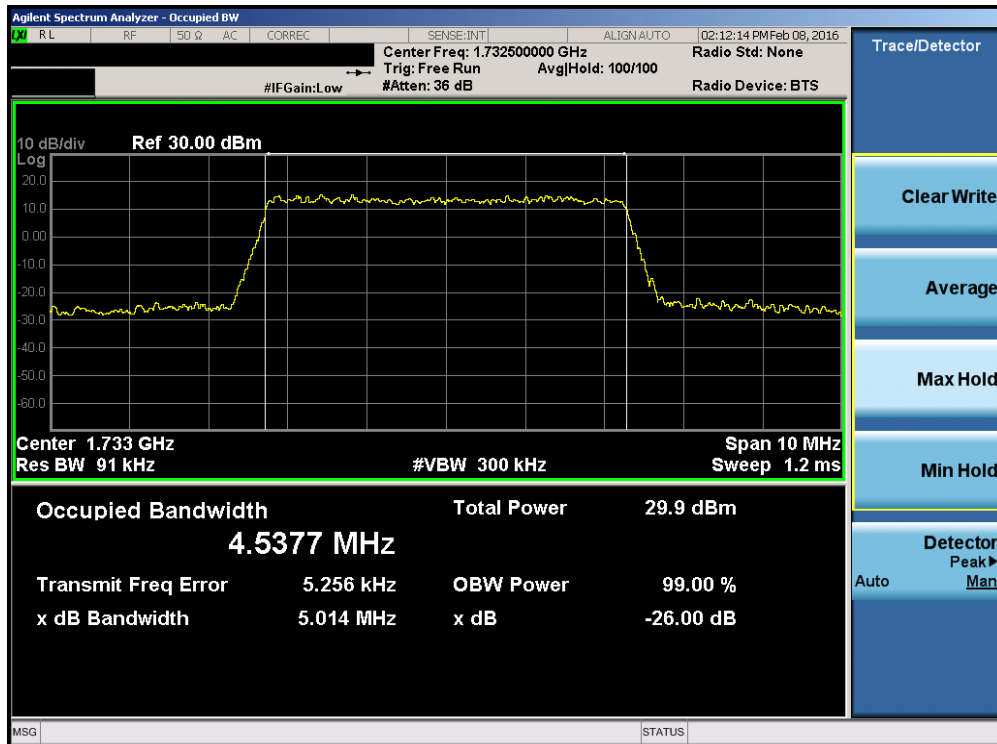


Plot 7-16. Occupied Bandwidth Plot (Band 4 – 3.0MHz 16-QAM – RB Size 15)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 21 of 115

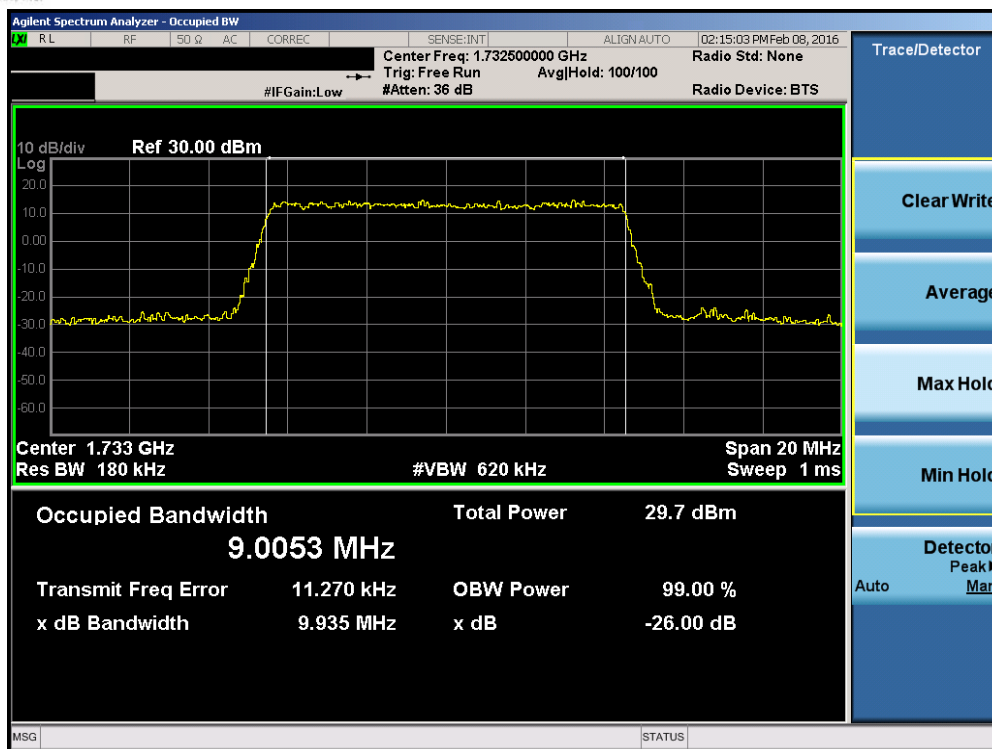


Plot 7-17. Occupied Bandwidth Plot (Band 4 – 5.0MHz QPSK – RB Size 25)

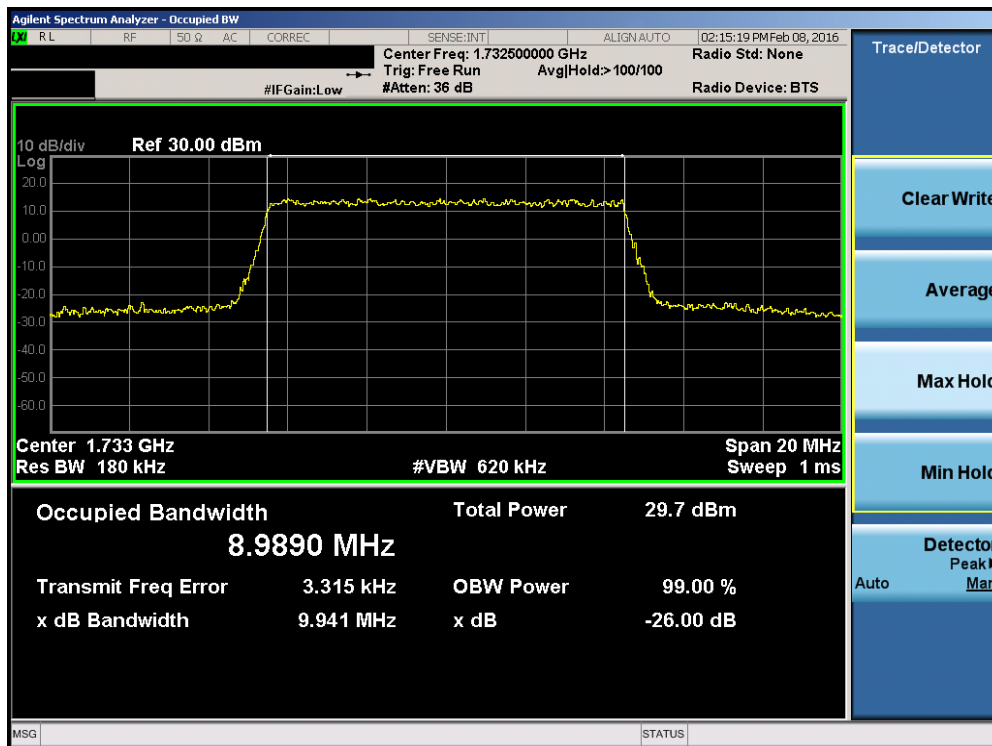


Plot 7-18. Occupied Bandwidth Plot (Band 4 – 5.0MHz 16-QAM – RB Size 25)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 22 of 115

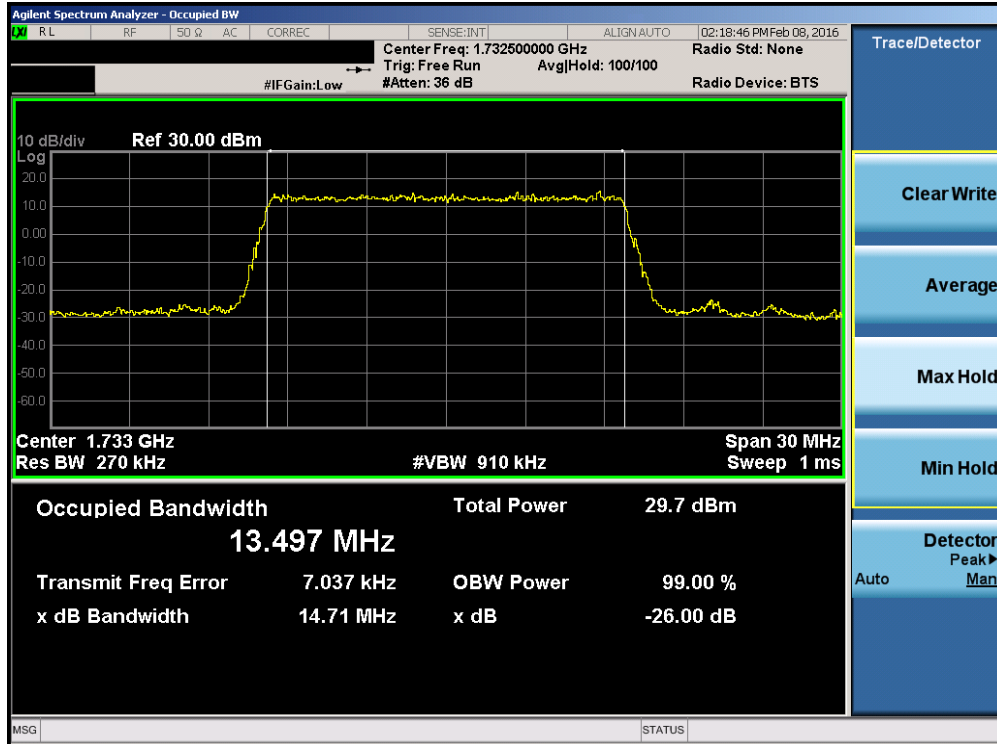


Plot 7-19. Occupied Bandwidth Plot (Band 4 – 10.0MHz QPSK – RB Size 50)

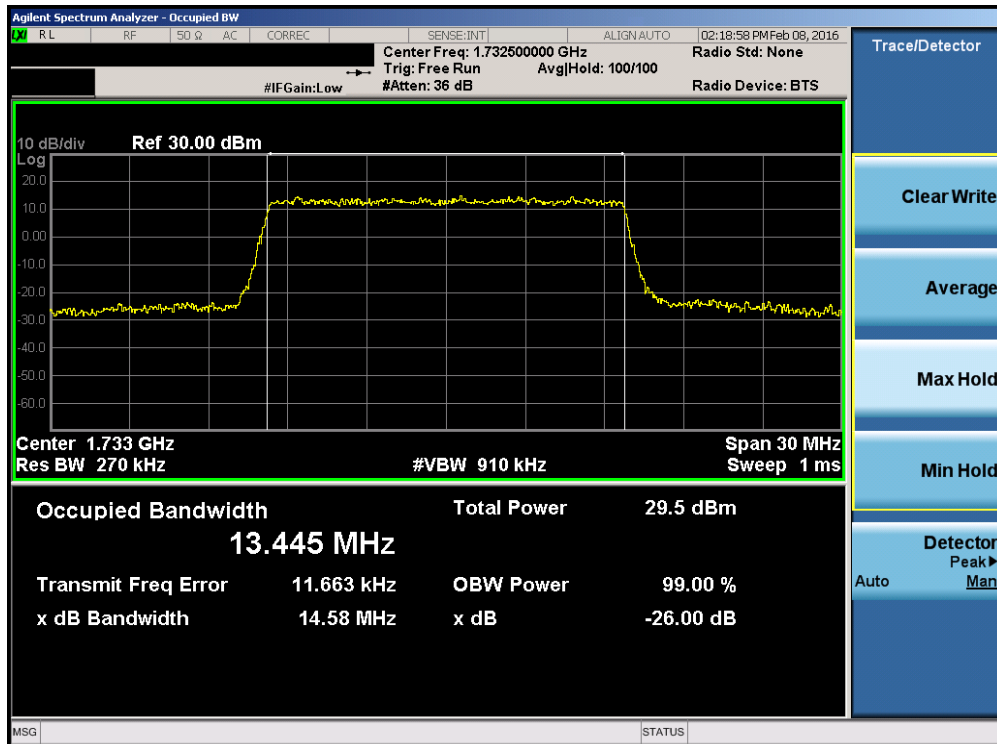


Plot 7-20. Occupied Bandwidth Plot (Band 4 – 10.0MHz 16-QAM – RB Size 50)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 23 of 115

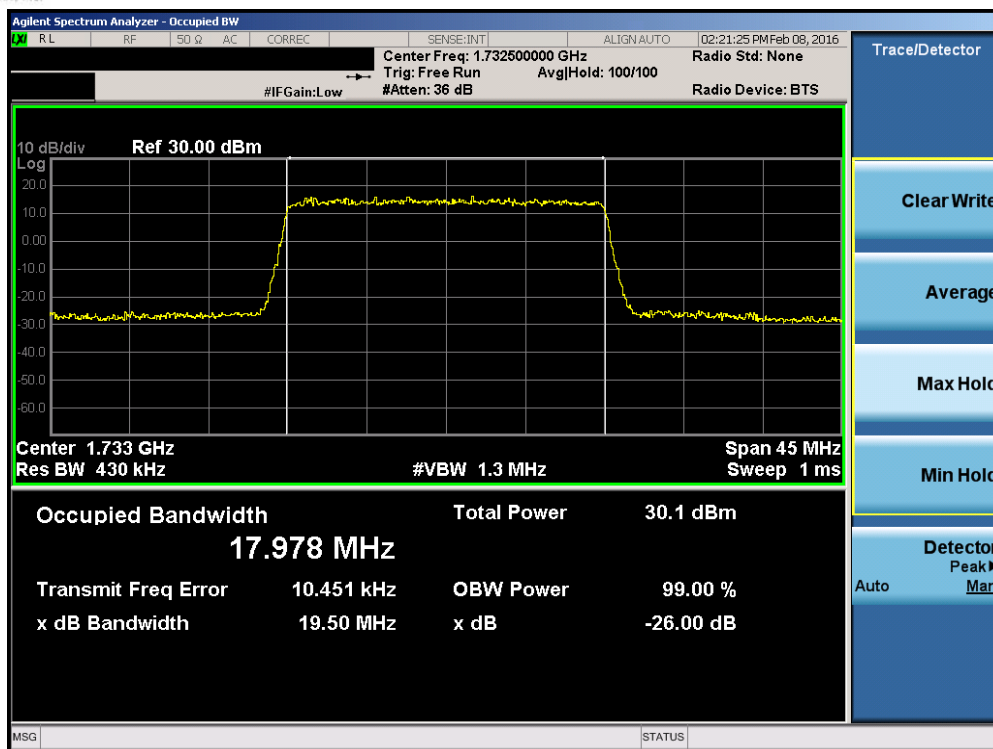


Plot 7-21. Occupied Bandwidth Plot (Band 4 – 15.0MHz QPSK – RB Size 75)

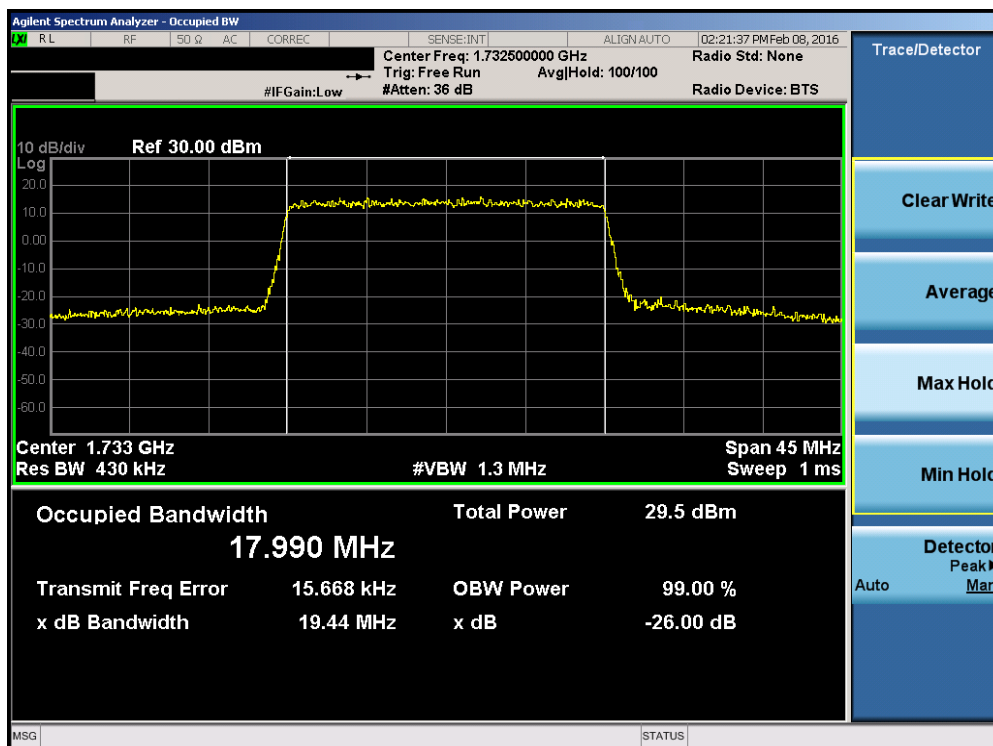


Plot 7-22. Occupied Bandwidth Plot (Band 4 – 15.0MHz 16-QAM – RB Size 75)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 24 of 115

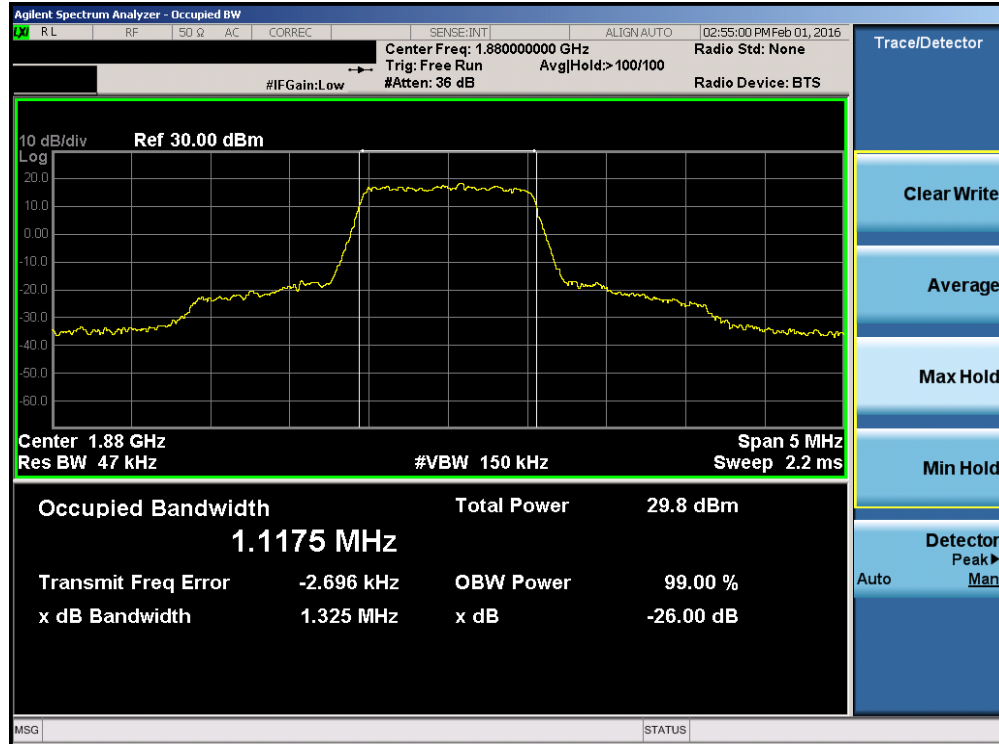


Plot 7-23. Occupied Bandwidth Plot (Band 4 – 20.0MHz QPSK – RB Size 100)

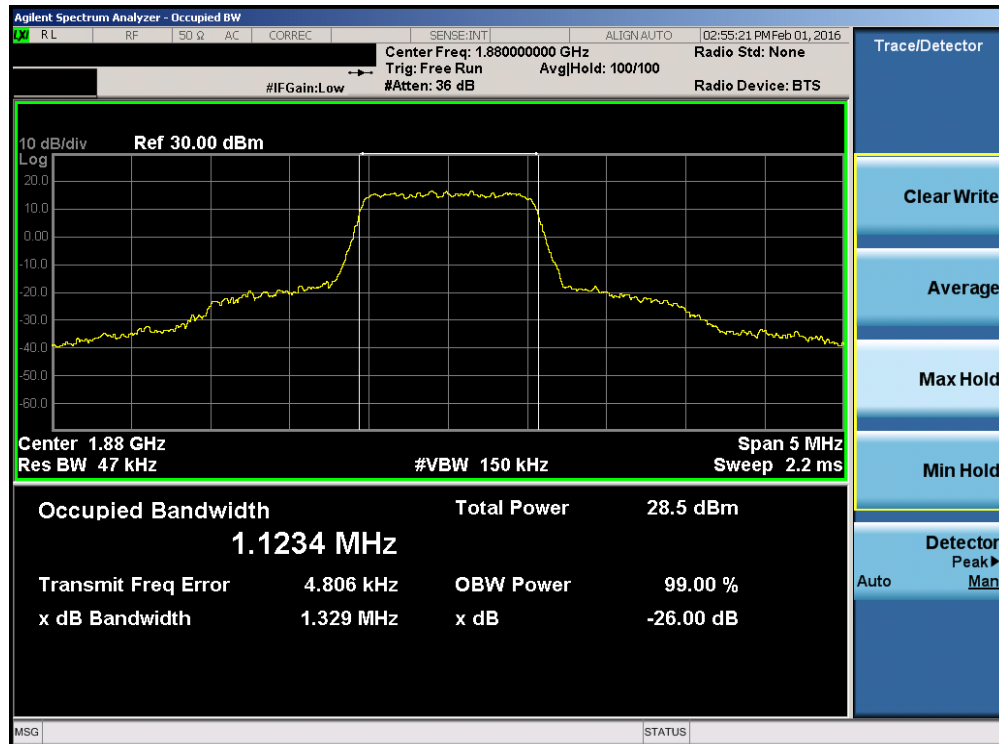


Plot 7-24. Occupied Bandwidth Plot (Band 4 – 20.0MHz 16-QAM – RB Size 100)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 25 of 115

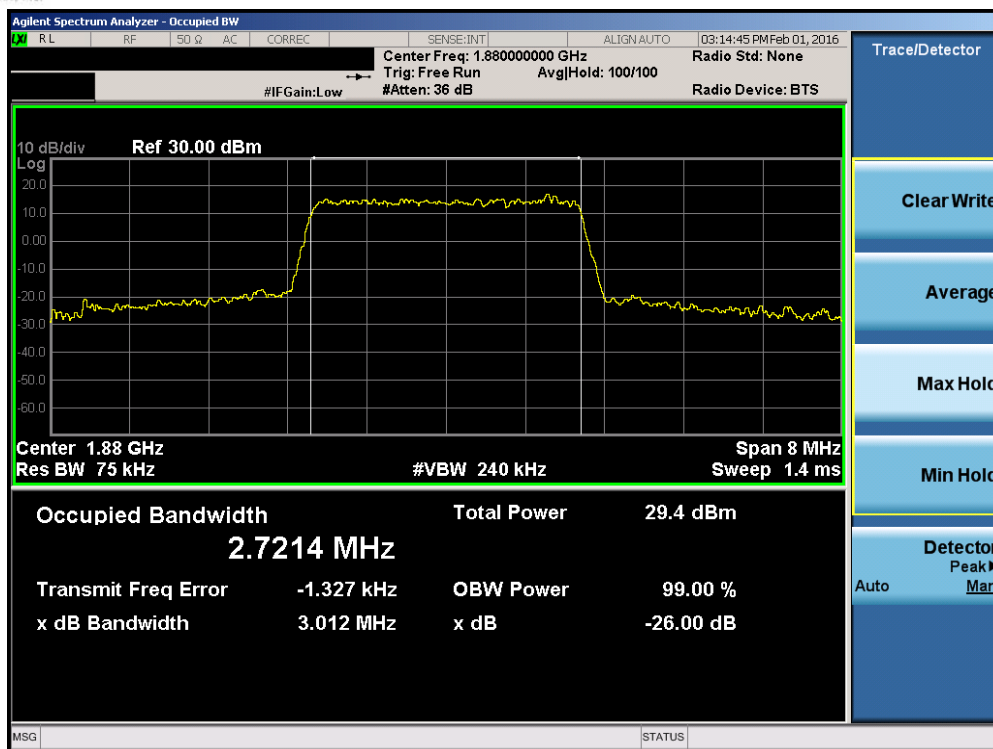


Plot 7-25. Occupied Bandwidth Plot (Band 2 – 1.4MHz QPSK – RB Size 6)

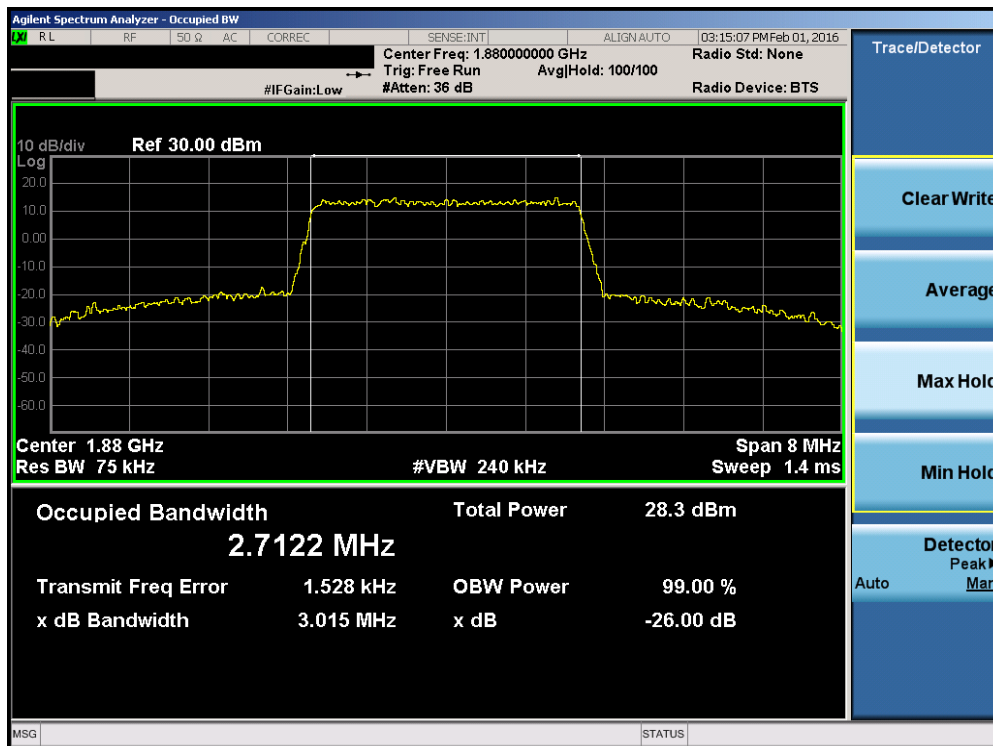


Plot 7-26. Occupied Bandwidth Plot (Band 2 – 1.4MHz 16-QAM – RB Size 6)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 26 of 115

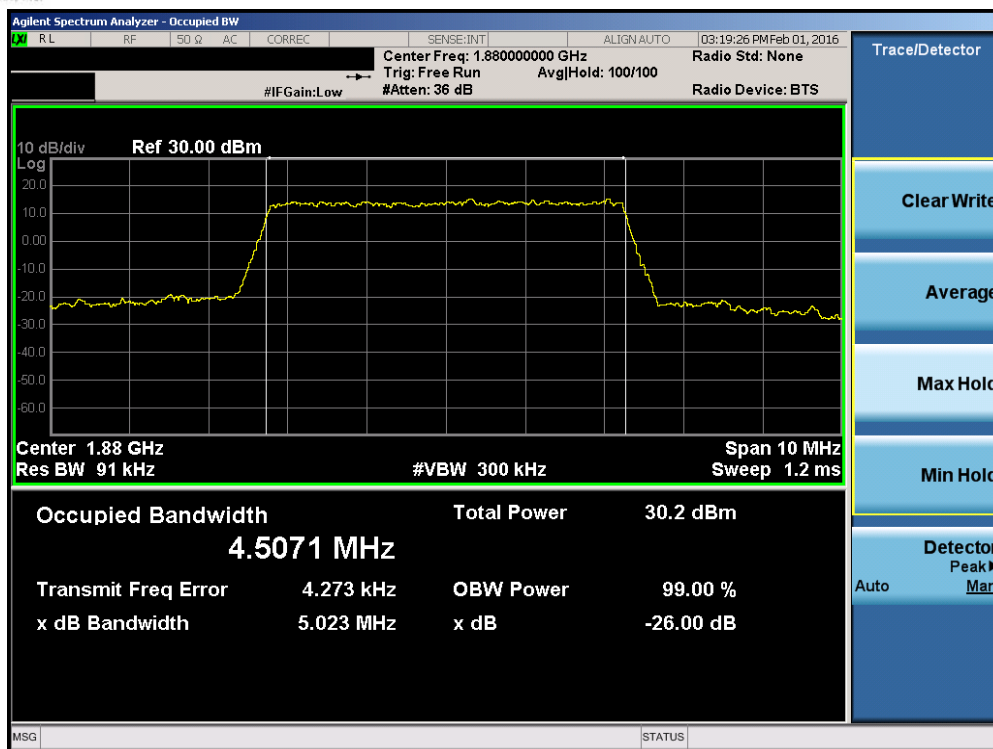


Plot 7-27. Occupied Bandwidth Plot (Band 2 – 3.0MHz QPSK – RB Size 15)

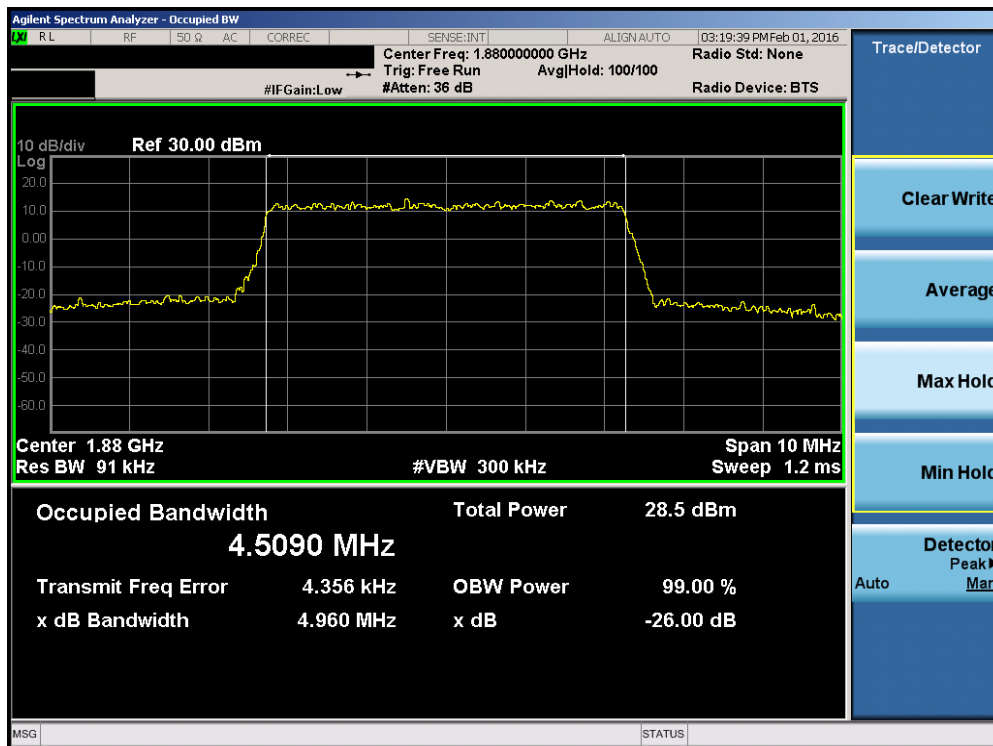


Plot 7-28. Occupied Bandwidth Plot (Band 2 – 3.0MHz 16-QAM – RB Size 15)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 27 of 115

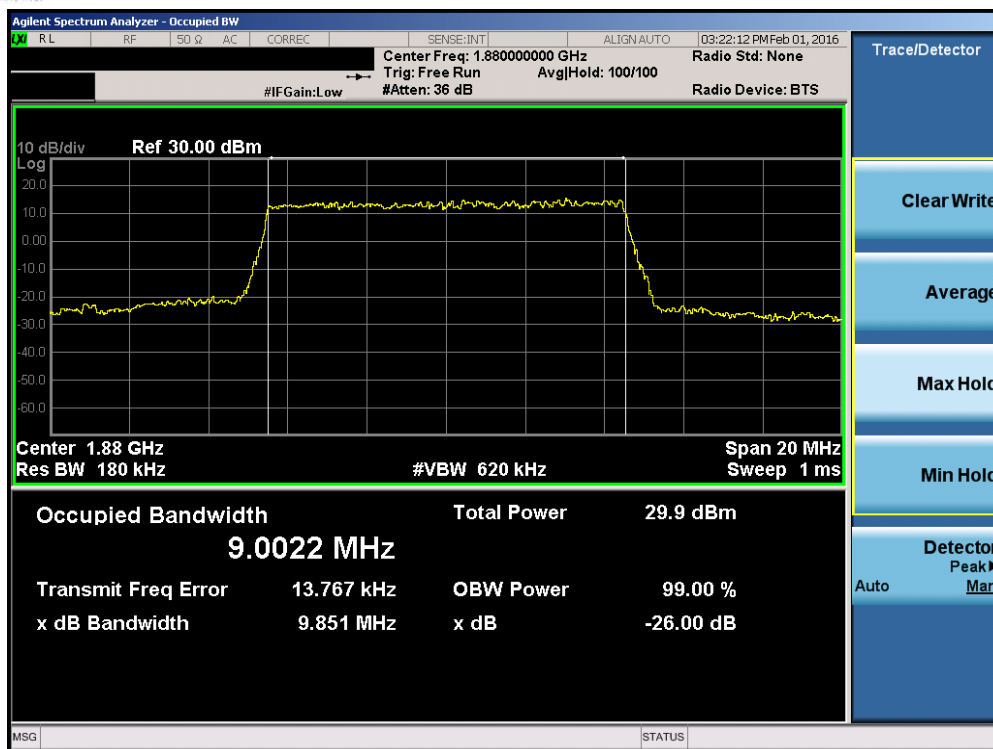


Plot 7-29. Occupied Bandwidth Plot (Band 2 – 5.0MHz QPSK – RB Size 25)

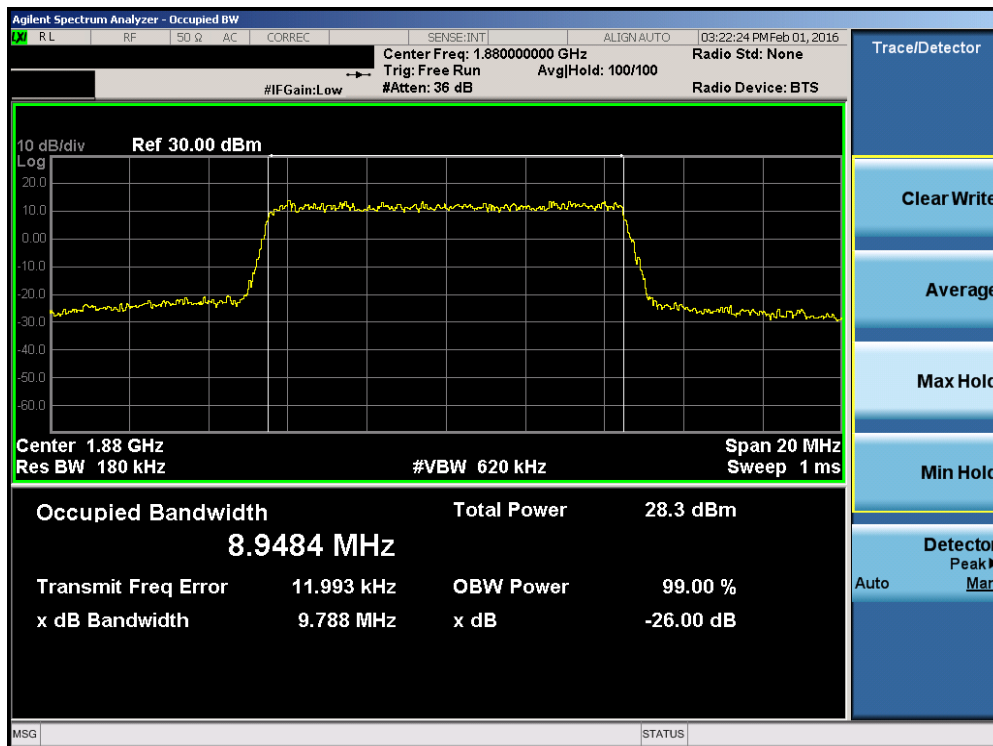


Plot 7-30. Occupied Bandwidth Plot (Band 2 – 5.0MHz 16-QAM – RB Size 25)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 28 of 115

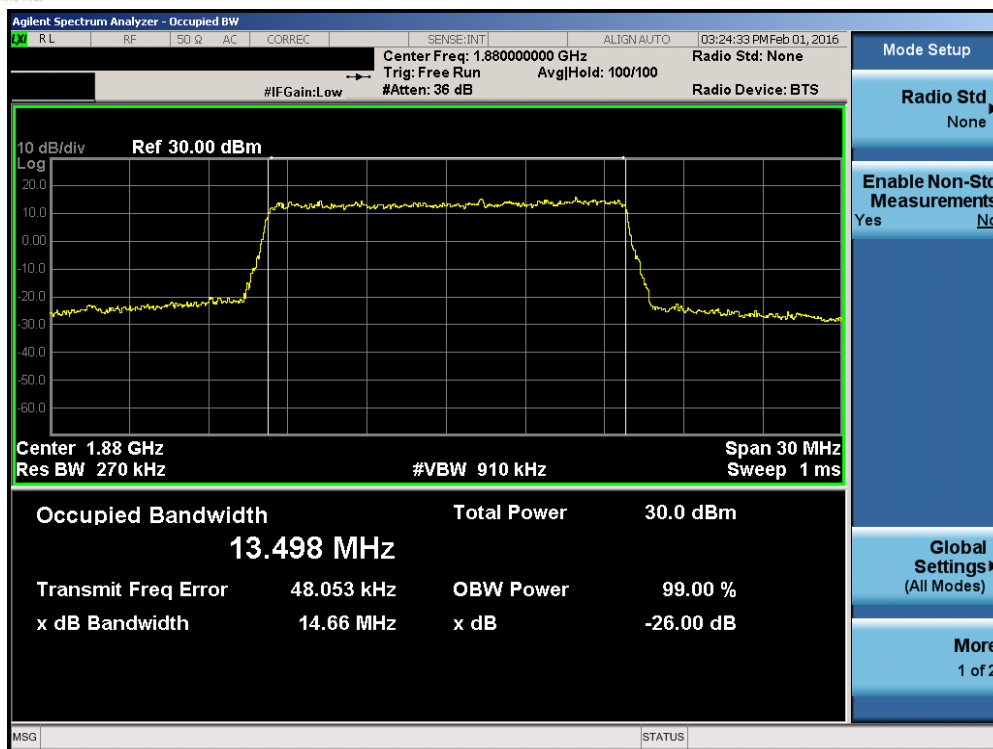


Plot 7-31. Occupied Bandwidth Plot (Band 2 – 10.0MHz QPSK – RB Size 50)

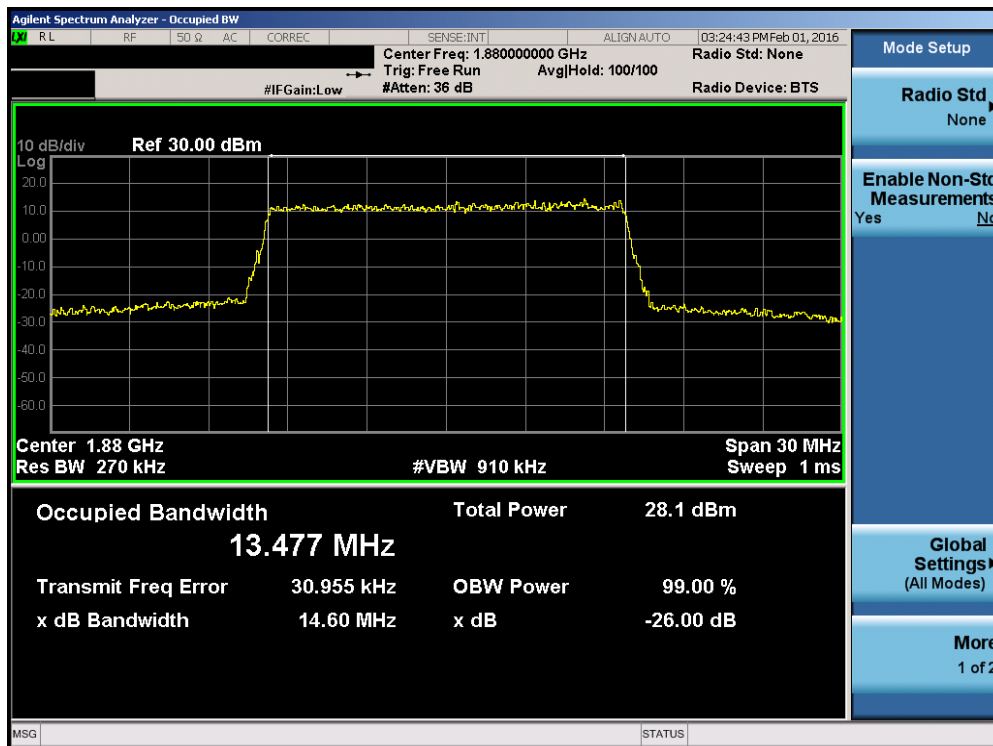


Plot 7-32. Occupied Bandwidth Plot (Band 2 – 10.0MHz 16-QAM – RB Size 50)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 29 of 115

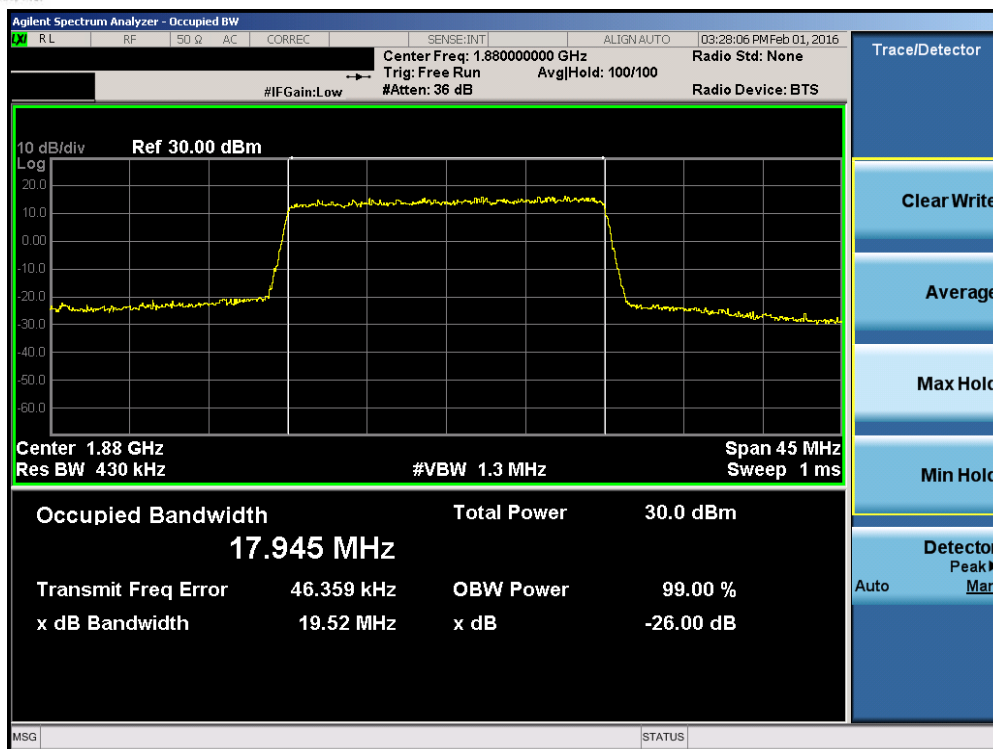


Plot 7-33. Occupied Bandwidth Plot (Band 2 – 15.0MHz QPSK – RB Size 75)

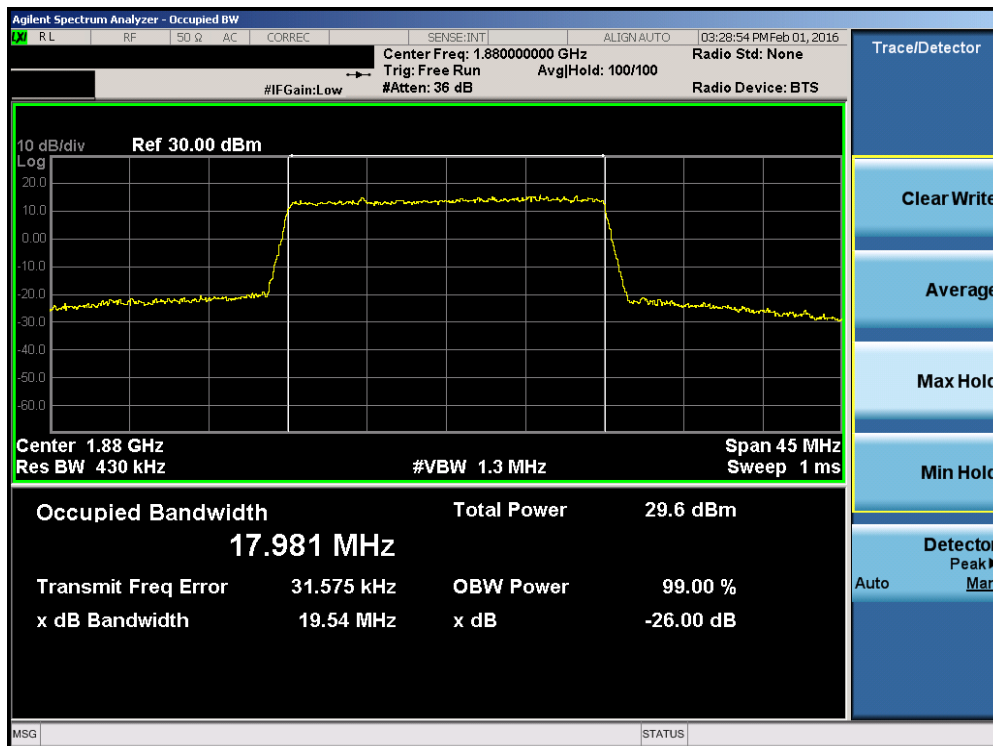


Plot 7-34. Occupied Bandwidth Plot (Band 2 – 15.0MHz 16-QAM – RB Size 75)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 30 of 115



Plot 7-35. Occupied Bandwidth Plot (Band 2 – 20.0MHz QPSK – RB Size 100)



Plot 7-36. Occupied Bandwidth Plot (Band 2 – 20.0MHz 16-QAM – RB Size 100)

FCC ID: A3LSMJ320VPP	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1601280165-R1.A3L	Test Dates: 1/29-2/27/2016	EUT Type: Portable Handset		Page 31 of 115